

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				2	*****
				3	*
				4	*            Zvector E6 instruction tests for VRR-i encoded:
				5	*
				6	*            E650 VCVB        - VECTOR CONVERT TO BINARY    (32)
				7	*            E652 VCVBG        - VECTOR CONVERT TO BINARY    (64)
				8	*
				9	*            James Wekel June 2024
				10	*****
				11	
				12	*****
				13	*
				14	*            basic instruction tests
				15	*
				16	*****
				17	*    This program tests proper functioning of the z/arch E6 VRR-i vector
				18	*    convert to binary instructions. Exceptions are not tested.
				19	*
				20	*    PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21	*    obvious coding errors. None of the tests are thorough. They are
				22	*    NOT designed to test all aspects of any of the instructions.
				23	*
				24	*****
				25	*
				26	*    *Testcase zvector-e6-11-convertbinary: VECTOR E6 VRR-i instruction
				27	*    *
				28	*    *            Zvector E6 tests for VRR-i encoded instruction:
				29	*    *
				30	*    *            E650 VCVB        - VECTOR CONVERT TO BINARY    (32)
				31	*    *            E652 VCVBG        - VECTOR CONVERT TO BINARY    (64)
				32	*    *
				33	*    *    # -----
				34	*    *    #    This tests only the basic function of the instruction.
				35	*    *    #    Exceptions are NOT tested.
				36	*    *    # -----
				37	*    *
				38	*    main size        2
				39	*    numcpu           1
				40	*    sysclear
				41	*    archlvl         z/Arch
				42	*
				43	*    diag8cmd        enable    # (needed for messages to Hercules console)
				44	*    loadcore        "\$(testpath)/zvector-e6-11-convertbinary.core" 0x0
				45	*    diag8cmd        disable   # (reset back to default)
				46	*
				47	*    *Done
				48	*****
00000000		00000000	0000221F	50	ZVE6TST    START 0
				51	USING ZVE6TST, R0            Low core addressability
				52	
		00000140	00000000	53	SVOLDPSW EQU    ZVE6TST+X' 140'        z/Arch Supervisor call old PSW
00000000		00000000	000001A0	55	ORG    ZVE6TST+X' 1A0'        z/Architecture RESTART PSW







LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						139	*****
						140	* cc was not as expected
						141	*****
00000268	E310	0001	0082	00000268	00000001	142	CCMSG EQU *
0000026E	E310	5007	0076		00000001	143	XG R1, R1
00000274	5410	8288			00000007	144	LB R1, M3 m3 has CS bit
00000278	4780	804C			00000488	145	N R1, =F' 1' get CS (CC set) bit
					0000024C	146	BZ TESTREST ignore if not set
						147	*
						148	* extract CC extracted PSW
						149	*
0000027C	5810	8ED4			000010D4	150	L R1, CCPSW
00000280	8810	000C			0000000C	151	SRL R1, 12
00000284	5410	828C			0000048C	152	N R1, =XL4' 3'
00000288	4210	8EDC			000010DC	153	STC R1, CCFOUND save cc
						154	*
						155	* FILL IN MESSAGE
						156	*
0000028C	4820	5004			00000004	157	LH R2, TNUM get test number and convert
00000290	4E20	8EC4			000010C4	158	CVD R2, DECNUM
00000294	D211	8EAE	8E98	000010AE	00001098	159	MVC PRT3, EDIT
0000029A	DE11	8EAE	8EC4	000010AE	000010C4	160	ED PRT3, DECNUM
000002A0	D202	8E53	8EBB	00001053	000010BB	161	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						162	
000002A6	D207	8E70	500A	00001070	0000000A	163	MVC CCPRTNAME, OPNAME fill in message with instruction
						164	
000002AC	B982	0022				165	XGR R2, R2 get CC as U8
000002B0	4320	5008			00000008	166	IC R2, CC
000002B4	4E20	8EC4			000010C4	167	CVD R2, DECNUM and convert
000002B8	D211	8EAE	8E98	000010AE	00001098	168	MVC PRT3, EDIT
000002BE	DE11	8EAE	8EC4	000010AE	000010C4	169	ED PRT3, DECNUM
000002C4	D200	8E86	8EBD	00001086	000010BD	170	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						171	
000002CA	B982	0022				172	XGR R2, R2 get CCFOUND as U8
000002CE	4320	8EDC			000010DC	173	IC R2, CCFOUND
000002D2	4E20	8EC4			000010C4	174	CVD R2, DECNUM and convert
000002D6	D211	8EAE	8E98	000010AE	00001098	175	MVC PRT3, EDIT
000002DC	DE11	8EAE	8EC4	000010AE	000010C4	176	ED PRT3, DECNUM
000002E2	D200	8E96	8EBD	00001096	000010BD	177	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						178	
000002E8	4100	0055			00000055	179	LA R0, CCPRTLNG message length
000002EC	4110	8E43			00001043	180	LA R1, CCPRTLNE messagfe address
000002F0	45F0	8160			00000360	181	BAL R15, RPTERROR
						182	
000002F4	47F0	8142			00000342	183	B FAILCONT

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				185	*****
				186	* result not as expected:
				187	* issue message with test number, instruction under test
				188	* and instruction 12
				189	*****
		000002F8	00000001	190	FAILMSG EQU *
000002F8	4820 5004		00000004	191	LH R2, TNUM get test number and convert
000002FC	4E20 8EC4		000010C4	192	CVD R2, DECNUM
00000300	D211 8EAE 8E98	000010AE	00001098	193	MVC PRT3, EDIT
00000306	DE11 8EAE 8EC4	000010AE	000010C4	194	ED PRT3, DECNUM
0000030C	D202 8E14 8EBB	00001014	000010BB	195	MVC PRTNUM(3), PRT3+13 fill in message with test #
				196	
00000312	D207 8E2F 500A	0000102F	0000000A	197	MVC PRTNAME, OPNAME fill in message with instruction
				198	
00000318	B982 0022			199	XGR R2, R2 get M3 as U8
0000031C	4320 5007		00000007	200	IC R2, M3 and convert
00000320	4E20 8EC4		000010C4	201	CVD R2, DECNUM
00000324	D211 8EAE 8E98	000010AE	00001098	202	MVC PRT3, EDIT
0000032A	DE11 8EAE 8EC4	000010AE	000010C4	203	ED PRT3, DECNUM
00000330	D201 8E40 8EBC	00001040	000010BC	204	MVC PRTM3(2), PRT3+14 fill in message with m3 field
				205	
00000336	4100 003F		0000003F	206	LA R0, PRTLNG message length
0000033A	4110 8E04		00001004	207	LA R1, PRTLNE messagfe address
0000033E	45F0 8160		00000360	208	BAL R15, RPTERROR
				210	*****
				211	* continue after a failed test
				212	*****
		00000342	00000001	213	FAILCONT EQU *
00000342	5800 8288		00000488	214	L R0, =F' 1' set GLOBAL failed test indicator
00000346	5000 8E00		00001000	215	ST R0, FAILED
				216	
0000034A	41C0 C004		00000004	217	LA R12, 4(0, R12) next test address
0000034E	47F0 802A		0000022A	218	B NEXTE6
				220	*****
				221	* end of testing; set ending psw
				222	*****
		00000352	00000001	223	ENDTEST EQU *
00000352	5810 8E00		00001000	224	L R1, FAILED did a test fail?
00000356	1211			225	LTR R1, R1
00000358	4780 8260		00000460	226	BZ EOJ No, exit
0000035C	47F0 8278		00000478	227	B FAILTEST Yes, exit with BAD PSW
				228	









LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				289	*****
				290	*            Normal completion or Abnormal termination PSWs
				291	*****
00000450	00020001 80000000			293	E0JPSW    DC    0D' 0' , X' 0002000180000000' , AD(0)
00000460	B2B2 8250		00000450	295	E0J            LPSWE E0JPSW            Normal completion
00000468	00020001 80000000			297	FAILPSW    DC    0D' 0' , X' 0002000180000000' , AD(X' BAD' )
00000478	B2B2 8268		00000468	299	FAILTEST    LPSWE FAILPSW            Abnormal termination
				301	*****
				302	*            Working Storage
				303	*****
0000047C	00000000			305	CTLRO       DS    F            CRO
00000480	00000000			306	DS    F
				307	
00000484	00002158			308	E6TADR      DC    A(E6TESTS)            address of E6 test table
00000488				310	LTORG ,            Literals pool
00000488	00000001			311	=F' 1'
0000048C	00000003			312	=XL4' 3'
00000490	0000			313	=H' 0'
00000492	005F			314	=AL2(L' MSGMSG)
				315	
				316	*            some constants
				317	
	00000400	00000001		318	K            EQU    1024            One KB
	00001000	00000001		319	PAGE        EQU    (4*K)            Size of one page
	00010000	00000001		320	K64         EQU    (64*K)            64 KB
	00100000	00000001		321	MB          EQU    (K*K)            1 MB
				322	
				323	
	AABBCCDD	00000001		324	REG2PATT    EQU    X' AABBCCDD'            Polluted Register pattern
	000000DD	00000001		325	REG2LOW     EQU            X' DD'            (last byte above)

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT	
					327	*=====
					328	*
					329	* NOTE: start data on an address that is easy to display
					330	* within Hercules
					331	*
					332	*=====
					333	
00000494			00000494	00001000	334	ORG ZVE6TST+X' 1000'
00001000	00000000				335	FAILED DC F' 0' some test failed?
					337	*****
					338	* TEST failed : result messgae
					339	*****
					340	*
					341	* failed message and associated editting
					342	*
00001004	40404040	40404040			343	PRTLNE DC C' Test # '
00001014	A7A7A7				344	PRTNUM DC C' xxx'
00001017	40868189	93858440			345	DC C' failed for instruction '
0000102F	A7A7A7A7	A7A7A7A7			346	PRTNAME DC CL8' xxxxxxxx'
00001037	40A689A3	884094F3			347	DC C' with m3='
00001040	A7A7				348	PRTMB DC C' xx'
00001042	4B				349	DC C'.'
			0000003F	00000001	350	PRTLNG EQU *- PRTLNE
					352	*****
					353	* TEST failed : CC message
					354	*****
					355	*
					356	* failed message and associated editting
					357	*
00001043	40404040	40404040			358	CCPRTLNE DC C' Test # '
00001053	A7A7A7				359	CCPRTNUM DC C' xxx'
00001056	40A69996	95874083			360	DC c' wrong cc for instruction '
00001070	A7A7A7A7	A7A7A7A7			361	CCPRTNAME DC CL8' xxxxxxxx'
00001078	4085A797	8583A385			362	DC C' expected: cc='
00001086	A7				363	CCPRTEXP DC C' x'
00001087	6B				364	DC C' ,'
00001088	40998583	8589A585			365	DC C' received: cc='
00001096	A7				366	CCPRTGOT DC C' x'
00001097	4B				367	DC C'.'
			00000055	00000001	368	CCPRTLNG EQU *- CCPRTLNE





LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				425 *****	
				426 * <b>Macros to help build test tables</b>	
				427 * -----	
				428 * <b>VRR_I Macro to help build test tables</b>	
				429 *****	
				430 <b>MACRO</b>	
				431 <b>VRR_I &amp;INST, &amp;MB, &amp;CC</b>	
				432 . *	&INST - VRS-d instruction under test
				433 . *	&MB - P2 (bit 0), P1 (bit 2) and
				434 . *	CS (bit 3)
				435 . *	&CC - expected CC
				436 . *	
				437 . *	note: M4 - bit 0 IOM (always 0)
				438 . *	
				439 . *	
				440	LCLA &XCC(4) &CC has mask values for FAILED condition codes
				441 &XCC(1) SETA 7	CC != 0
				442 &XCC(2) SETA 11	CC != 1
				443 &XCC(3) SETA 13	CC != 2
				444 &XCC(4) SETA 14	CC != 3
				445	
				446	GBLA &TNUM
				447 &TNUM SETA &TNUM+1	
				448	
				449	DS OFD
				450	USING *, R5
				451	
				452 T&TNUM DC A(X&TNUM)	address of test routine
				453	DC H' &TNUM
				454	DC XL1' 00'
				455	DC HL1' &MB'
				456	DC HL1' &CC'
				457	DC HL1' &XCC(&CC+1)'
				458	
				459	DC CL8' &INST'
				460	DC A(16)
				461 REA&TNUM DC A(RE&TNUM)	result length
				462 . *	result address
				463 *	
				464 X&TNUM DS OF	INSTRUCTION UNDER TEST ROUTINE
				465	LG R1, R1FUDGE
				466	VL V1, RE&TNUM+8
				467	
				468	&INST R1, V1, &MB
				469	
				470	STG R1, R10OUTPUT
				471	EPSW R2, R0
				472	ST R2, CCPSW
				473	
				474	BR R11
				475	
				476 RE&TNUM DC OF	pollute R1
				477	DROP R5
				478	
				479	MEND
					get V1 source
					test instruction
					save
					exptract psw
					to save CC
					return

481	*****		
482	*	PTTABLE Macro to generate table of pointers to individual tests	
483	*****		
484			
485		MACRO	
486		PTTABLE	
487		GBLA	&TNUM
488		LCLA	&CUR
489	&CUR	SETA	1
490	. *		
491	TTABLE	DS	OF
492	. LOOP	ANOP	
493	. *		
494		DC	A(T&CUR) address of test
495	. *		
496	&CUR	SETA	&CUR+1
497		AIF	(&CUR LE &TNUM) . LOOP
498	*		
499		DC	A(0) END OF TABLE
500		DC	A(0)
501	. *		
502		MEND	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				504 *****	
				505 * E6 VRR_I tests	
				506 *****	
00001180		00000000	0000221F	507 ZVE6TST CSECT ,	
				508 DS 0F	
				510 PRINT DATA	
				511 *	
				512 * E650 VCVB - VECTOR CONVERT TO BINARY (32)	
				513 * E652 VCVBG - VECTOR CONVERT TO BINARY (64)	
				514 *	
				515 * VRR_I instr, m3, m4	
				516 * followed by	
				517 * r1 - expected result (64 bits) (even for VCVB)	
				518 * v1 - 16 byte packed decimal source	
				519	
				520 * -----	
				521 * VCVB - VECTOR CONVERT TO BINARY (32)	
				522 * -----	
				523 * VCVB simple	
00001180				524 VRR_I VCVB, 1, 0	
00001180		00001180		525+ DS 0FD	
00001180	0000119C			526+ USING *, R5	base for test data and test routine
00001184	0001			527+T1 DC A(X1)	address of test routine
00001186	00			528+ DC H' 1'	test number
00001187	01			529+ DC XL1' 00'	
00001188	00			530+ DC HL1' 1'	&MB
00001189	07			531+ DC HL1' 0'	cc
0000118A	E5C3E5C2 40404040			532+ DC HL1' 7'	cc failed mask
00001194	00000010			533+ DC CL8' VCVB'	instruction name
00001198	000011C0			534+ DC A(16)	result length
				535+REA1 DC A(RE1)	result address
				536+*	INSTRUCTION UNDER TEST ROUTINE
0000119C				537+X1 DS 0F	
0000119C	E310 8EE0 0004		000010E0	538+ LG R1, R1FUDGE	pollute R1
000011A2	E710 5048 0006		000011C8	539+ VL V1, RE1+8	get V1 source
000011A8	E611 0010 0050			540+ VCVB R1, V1, 1	test instruction
000011AE	E310 8F18 0024		00001118	541+ STG R1, R10UTPUT	save
000011B4	B98D 0020			542+ EPSW R2, R0	exptract psw
000011B8	5020 8ED4		000010D4	543+ ST R2, CCPSW	to save CC
000011BC	07FB			544+ BR R11	return
000011C0				545+RE1 DC 0F	
000011C0				546+ DROP R5	
000011C0	AABBCCDD 0000000A			547 DC XL08' AABBCCDD0000000A'	R1 result
000011C8	00000000 00000000			548 DC XL16' 0000000000000000000000000000000010C'	V1 source
000011D0	00000000 0000010C				
				549	
000011D8				550 VRR_I VCVB, 1, 0	
000011D8		000011D8		551+ DS 0FD	
000011D8	000011F4			552+ USING *, R5	base for test data and test routine
000011DC	0002			553+T2 DC A(X2)	address of test routine
000011DE	00			554+ DC H' 2'	test number
000011DE	00			555+ DC XL1' 00'	
000011DF	01			556+ DC HL1' 1'	&MB
000011E0	00			557+ DC HL1' 0'	cc



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000011E1	07			558+	DC	HL1' 7'	cc failed mask
000011E2	E5C3E5C2 40404040			559+	DC	CL8' VCVB'	instruction name
000011EC	00000010			560+	DC	A(16)	result length
000011F0	00001218			561+REA2	DC	A(RE2)	result address
				562+*			INSTRUCTION UNDER TEST ROUTINE
000011F4				563+X2	DS	OF	
000011F4	E310 8EE0 0004		000010E0	564+	LG	R1, R1FUDGE	pollute R1
000011FA	E710 9020 0006		00001220	565+	VL	V1, RE2+8	get V1 source
00001200	E611 0010 0050			566+	VCVB	R1, V1, 1	test instruction
00001206	E310 8F18 0024		00001118	567+	STG	R1, R10UTPUT	save
0000120C	B98D 0020			568+	EPSW	R2, R0	exptract psw
00001210	5020 8ED4		000010D4	569+	ST	R2, CCPSW	to save CC
00001214	07FB			570+	BR	R11	return
00001218				571+RE2	DC	OF	
00001218				572+	DROP	R5	
00001218	AABBCCDD FFFFFFFF6			573	DC	XL08' AABBCCDDFFFFFFF6'	R1 result
00001220	00000000 00000000			574	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001228	00000000 0000010D						
				575			
				576	VRR_I	VCVB, 1, 0	
00001230				577+	DS	OFD	
00001230		00001230		578+	USING	*, R5	base for test data and test routine
00001230	0000124C			579+T3	DC	A(X3)	address of test routine
00001234	0003			580+	DC	H' 3'	test number
00001236	00			581+	DC	XL1' 00'	
00001237	01			582+	DC	HL1' 1'	&MB
00001238	00			583+	DC	HL1' 0'	cc
00001239	07			584+	DC	HL1' 7'	cc failed mask
0000123A	E5C3E5C2 40404040			585+	DC	CL8' VCVB'	instruction name
00001244	00000010			586+	DC	A(16)	result length
00001248	00001270			587+REA3	DC	A(RE3)	result address
				588+*			INSTRUCTION UNDER TEST ROUTINE
0000124C				589+X3	DS	OF	
0000124C	E310 8EE0 0004		000010E0	590+	LG	R1, R1FUDGE	pollute R1
00001252	E710 5048 0006		00001278	591+	VL	V1, RE3+8	get V1 source
00001258	E611 0010 0050			592+	VCVB	R1, V1, 1	test instruction
0000125E	E310 8F18 0024		00001118	593+	STG	R1, R10UTPUT	save
00001264	B98D 0020			594+	EPSW	R2, R0	exptract psw
00001268	5020 8ED4		000010D4	595+	ST	R2, CCPSW	to save CC
0000126C	07FB			596+	BR	R11	return
00001270				597+RE3	DC	OF	
00001270				598+	DROP	R5	
00001270	AABBCCDD 0008A160			599	DC	XL08' AABBCCDD0008A160'	R1 result
00001278	00000000 00000000			600	DC	XL16' 0000000000000000000000000565600C'	V1 source
00001280	00000000 0565600C						
				601			
				602	VRR_I	VCVB, 1, 0	
00001288				603+	DS	OFD	
00001288		00001288		604+	USING	*, R5	base for test data and test routine
00001288	000012A4			605+T4	DC	A(X4)	address of test routine
0000128C	0004			606+	DC	H' 4'	test number
0000128E	00			607+	DC	XL1' 00'	
0000128F	01			608+	DC	HL1' 1'	&MB
00001290	00			609+	DC	HL1' 0'	cc
00001291	07			610+	DC	HL1' 7'	cc failed mask
00001292	E5C3E5C2 40404040			611+	DC	CL8' VCVB'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000129C	00000010			612+	DC	A(16)	result length
000012A0	000012C8			613+REA4	DC	A(RE4)	result address
				614+*			INSTRUCTION UNDER TEST ROUTINE
000012A4				615+X4	DS	0F	
000012A4	E310 8EE0 0004		000010E0	616+	LG	R1, R1FUDGE	pollute R1
000012AA	E710 5048 0006		000012D0	617+	VL	V1, RE4+8	get V1 source
000012B0	E611 0010 0050			618+	VCVB	R1, V1, 1	test instruction
000012B6	E310 8F18 0024		00001118	619+	STG	R1, R10UTPUT	save
000012BC	B98D 0020			620+	EPSW	R2, R0	exptract psw
000012C0	5020 8ED4		000010D4	621+	ST	R2, CCPSW	to save CC
000012C4	07FB			622+	BR	R11	return
000012C8				623+RE4	DC	0F	
000012C8				624+	DROP	R5	
000012C8	AABBCCDD FFF75EA0			625	DC	XL08' AABBCCDDFFF75EA0'	R1 result
000012D0	00000000 00000000			626	DC	XL16' 0000000000000000000000000565600D'	V1 source
000012D8	00000000 0565600D			627			
				628	VRR_I	VCVB, 1, 0	INT_MAX
000012E0				629+	DS	0FD	
000012E0		000012E0		630+	USING	*, R5	base for test data and test routine
000012E0	000012FC			631+T5	DC	A(X5)	address of test routine
000012E4	0005			632+	DC	H' 5'	test number
000012E6	00			633+	DC	XL1' 00'	
000012E7	01			634+	DC	HL1' 1'	&MB
000012E8	00			635+	DC	HL1' 0'	cc
000012E9	07			636+	DC	HL1' 7'	cc failed mask
000012EA	E5C3E5C2 40404040			637+	DC	CL8' VCVB'	instruction name
000012F4	00000010			638+	DC	A(16)	result length
000012F8	00001320			639+REA5	DC	A(RE5)	result address
				640+*			INSTRUCTION UNDER TEST ROUTINE
000012FC				641+X5	DS	0F	
000012FC	E310 8EE0 0004		000010E0	642+	LG	R1, R1FUDGE	pollute R1
00001302	E710 5048 0006		00001328	643+	VL	V1, RE5+8	get V1 source
00001308	E611 0010 0050			644+	VCVB	R1, V1, 1	test instruction
0000130E	E310 8F18 0024		00001118	645+	STG	R1, R10UTPUT	save
00001314	B98D 0020			646+	EPSW	R2, R0	exptract psw
00001318	5020 8ED4		000010D4	647+	ST	R2, CCPSW	to save CC
0000131C	07FB			648+	BR	R11	return
00001320				649+RE5	DC	0F	
00001320				650+	DROP	R5	
00001320	AABBCCDD 7FFFFFFF			651	DC	XL08' AABBCCDD7FFFFFFF'	R1 result
00001328	00000000 00000000			652	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001330	00000214 7483647C			653			
				654	VRR_I	VCVB, 1, 0	INT_MIN
00001338				655+	DS	0FD	
00001338		00001338		656+	USING	*, R5	base for test data and test routine
00001338	00001354			657+T6	DC	A(X6)	address of test routine
0000133C	0006			658+	DC	H' 6'	test number
0000133E	00			659+	DC	XL1' 00'	
0000133F	01			660+	DC	HL1' 1'	&MB
00001340	00			661+	DC	HL1' 0'	cc
00001341	07			662+	DC	HL1' 7'	cc failed mask
00001342	E5C3E5C2 40404040			663+	DC	CL8' VCVB'	instruction name
0000134C	00000010			664+	DC	A(16)	result length
00001350	00001378			665+REA6	DC	A(RE6)	result address

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				666+*		INSTRUCTION UNDER TEST ROUTINE	
00001354				667+X6	DS	0F	
00001354	E310 8EE0 0004		000010E0	668+	LG	R1, R1FUDGE	pollute R1
0000135A	E710 5048 0006		00001380	669+	VL	V1, RE6+8	get V1 source
00001360	E611 0010 0050			670+	VCVB	R1, V1, 1	test instruction
00001366	E310 8F18 0024		00001118	671+	STG	R1, R10UTPUT	save
0000136C	B98D 0020			672+	EPSW	R2, R0	exptract psw
00001370	5020 8ED4		000010D4	673+	ST	R2, CCPSW	to save CC
00001374	07FB			674+	BR	R11	return
00001378				675+RE6	DC	0F	
00001378				676+	DROP	R5	
00001378	AABBCCDD 80000000			677	DC	XL08' AABBCCDD80000000'	R1 result
00001380	00000000 00000000			678	DC	XL16' 000000000000000000000002147483648D'	V1 source
00001388	00000214 7483648D						
				679			
00001390				680	VRR_I	VCVB, 3, 0	UINT_MAX
00001390		00001390		681+	DS	0FD	
00001390	000013AC			682+	USING	*, R5	base for test data and test routine
00001394	0007			683+T7	DC	A(X7)	address of test routine
00001396	00			684+	DC	H' 7'	test number
00001397	03			685+	DC	XL1' 00'	
00001398	00			686+	DC	HL1' 3'	&MB
00001398	00			687+	DC	HL1' 0'	cc
00001399	07			688+	DC	HL1' 7'	cc failed mask
0000139A	E5C3E5C2 40404040			689+	DC	CL8' VCVB'	instruction name
000013A4	00000010			690+	DC	A(16)	result length
000013A8	000013D0			691+REA7	DC	A(RE7)	result address
				692+*			INSTRUCTION UNDER TEST ROUTINE
000013AC				693+X7	DS	0F	
000013AC	E310 8EE0 0004		000010E0	694+	LG	R1, R1FUDGE	pollute R1
000013B2	E710 5048 0006		000013D8	695+	VL	V1, RE7+8	get V1 source
000013B8	E611 0030 0050			696+	VCVB	R1, V1, 3	test instruction
000013BE	E310 8F18 0024		00001118	697+	STG	R1, R10UTPUT	save
000013C4	B98D 0020			698+	EPSW	R2, R0	exptract psw
000013C8	5020 8ED4		000010D4	699+	ST	R2, CCPSW	to save CC
000013CC	07FB			700+	BR	R11	return
000013D0				701+RE7	DC	0F	
000013D0				702+	DROP	R5	
000013D0	AABBCCDD FFFFFFFF			703	DC	XL08' AABBCCDDFFFFFFFF'	R1 result
000013D8	00000000 00000000			704	DC	XL16' 000000000000000000000004294967295C'	V1 source
000013E0	00000429 4967295C						
				705			
000013E8				706	VRR_I	VCVB, 3, 3	UINT_MAX +1
000013E8		000013E8		707+	DS	0FD	
000013E8	00001404			708+	USING	*, R5	base for test data and test routine
000013EC	0008			709+T8	DC	A(X8)	address of test routine
000013EE	00			710+	DC	H' 8'	test number
000013EF	03			711+	DC	XL1' 00'	
000013F0	03			712+	DC	HL1' 3'	&MB
000013F1	0E			713+	DC	HL1' 3'	cc
000013F2	E5C3E5C2 40404040			714+	DC	HL1' 14'	cc failed mask
000013F2	E5C3E5C2 40404040			715+	DC	CL8' VCVB'	instruction name
000013FC	00000010			716+	DC	A(16)	result length
00001400	00001428			717+REA8	DC	A(RE8)	result address
				718+*			INSTRUCTION UNDER TEST ROUTINE
00001404				719+X8	DS	0F	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001404	E310 8EE0 0004		000010E0	720+	LG	R1, R1FUDGE	pollute R1
0000140A	E710 5048 0006		00001430	721+	VL	V1, RE8+8	get V1 source
00001410	E611 0030 0050			722+	VCVB	R1, V1, 3	test instruction
00001416	E310 8F18 0024		00001118	723+	STG	R1, R10UTPUT	save
0000141C	B98D 0020			724+	EPSW	R2, R0	exptract psw
00001420	5020 8ED4		000010D4	725+	ST	R2, CCPSW	to save CC
00001424	07FB			726+	BR	R11	return
00001428				727+RE8	DC	0F	
00001428				728+	DROP	R5	
00001428	AABBCCDD 00000000			729	DC	XL08' AABBCCDD00000000'	R1 result
00001430	00000000 00000000			730	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001438	00000429 4967296C						
				731			
				732	VRR_I	VCVB, 1, 3	
00001440				733+	DS	0FD	
00001440		00001440		734+	USING	*, R5	base for test data and test routine
00001440	0000145C			735+T9	DC	A(X9)	address of test routine
00001444	0009			736+	DC	H' 9'	test number
00001446	00			737+	DC	XL1' 00'	
00001447	01			738+	DC	HL1' 1'	&MB
00001448	03			739+	DC	HL1' 3'	cc
00001449	0E			740+	DC	HL1' 14'	cc failed mask
0000144A	E5C3E5C2 40404040			741+	DC	CL8' VCVB'	instruction name
00001454	00000010			742+	DC	A(16)	result length
00001458	00001480			743+REA9	DC	A(RE9)	result address
				744+*			INSTRUCTION UNDER TEST ROUTINE
0000145C				745+X9	DS	0F	
0000145C	E310 8EE0 0004		000010E0	746+	LG	R1, R1FUDGE	pollute R1
00001462	E710 5048 0006		00001488	747+	VL	V1, RE9+8	get V1 source
00001468	E611 0010 0050			748+	VCVB	R1, V1, 1	test instruction
0000146E	E310 8F18 0024		00001118	749+	STG	R1, R10UTPUT	save
00001474	B98D 0020			750+	EPSW	R2, R0	exptract psw
00001478	5020 8ED4		000010D4	751+	ST	R2, CCPSW	to save CC
0000147C	07FB			752+	BR	R11	return
00001480				753+RE9	DC	0F	
00001480				754+	DROP	R5	
00001480	AABBCCDD DF8E1660			755	DC	XL08' AABBCCDDDF8E1660'	R1 result
00001488	00000000 00000000			756	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001490	00001234 0565600C						
				757			
				758 * VCVB simple:	p2=1		
				759	VRR_I	VCVB, 9, 0	
00001498				760+	DS	0FD	
00001498		00001498		761+	USING	*, R5	base for test data and test routine
00001498	000014B4			762+T10	DC	A(X10)	address of test routine
0000149C	000A			763+	DC	H' 10'	test number
0000149E	00			764+	DC	XL1' 00'	
0000149F	09			765+	DC	HL1' 9'	&MB
000014A0	00			766+	DC	HL1' 0'	cc
000014A1	07			767+	DC	HL1' 7'	cc failed mask
000014A2	E5C3E5C2 40404040			768+	DC	CL8' VCVB'	instruction name
000014AC	00000010			769+	DC	A(16)	result length
000014B0	000014D8			770+REA10	DC	A(RE10)	result address
				771+*			INSTRUCTION UNDER TEST ROUTINE
000014B4				772+X10	DS	0F	
000014B4	E310 8EE0 0004		000010E0	773+	LG	R1, R1FUDGE	pollute R1



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000014BA	E710 5048 0006		000014E0	774+	VL	V1, RE10+8	get V1 source
000014C0	E611 0090 0050			775+	VCVB	R1, V1, 9	test instruction
000014C6	E310 8F18 0024		00001118	776+	STG	R1, R10UTPUT	save
000014CC	B98D 0020			777+	EPSW	R2, R0	exptract psw
000014D0	5020 8ED4		000010D4	778+	ST	R2, CCPSW	to save CC
000014D4	07FB			779+	BR	R11	return
000014D8				780+RE10	DC	0F	
000014D8				781+	DROP	R5	
000014D8	AABBCCDD 0000000A			782	DC	XL08' AABBCCDD0000000A'	R1 result
000014E0	00000000 00000000			783	DC	XL16' 0000000000000000000000000000000010C'	V1 source
000014E8	00000000 0000010C						
				784			
				785	VRR_I	VCVB, 9, 0	
000014F0				786+	DS	0FD	
000014F0		000014F0		787+	USING	*, R5	base for test data and test routine
000014F0	0000150C			788+T11	DC	A(X11)	address of test routine
000014F4	000B			789+	DC	H' 11'	test number
000014F6	00			790+	DC	XL1' 00'	
000014F7	09			791+	DC	HL1' 9'	&MB
000014F8	00			792+	DC	HL1' 0'	cc
000014F9	07			793+	DC	HL1' 7'	cc failed mask
000014FA	E5C3E5C2 40404040			794+	DC	CL8' VCVB'	instruction name
00001504	00000010			795+	DC	A(16)	result length
00001508	00001530			796+REA11	DC	A(RE11)	result address
				797+*			INSTRUCTION UNDER TEST ROUTINE
0000150C				798+X11	DS	0F	
0000150C	E310 8EE0 0004		000010E0	799+	LG	R1, R1FUDGE	pollute R1
00001512	E710 5048 0006		00001538	800+	VL	V1, RE11+8	get V1 source
00001518	E611 0090 0050			801+	VCVB	R1, V1, 9	test instruction
0000151E	E310 8F18 0024		00001118	802+	STG	R1, R10UTPUT	save
00001524	B98D 0020			803+	EPSW	R2, R0	exptract psw
00001528	5020 8ED4		000010D4	804+	ST	R2, CCPSW	to save CC
0000152C	07FB			805+	BR	R11	return
00001530				806+RE11	DC	0F	
00001530				807+	DROP	R5	
00001530	AABBCCDD 0000000A			808	DC	XL08' AABBCCDD0000000A'	R1 result
00001538	00000000 00000000			809	DC	XL16' 0000000000000000000000000000000010D'	V1 source
00001540	00000000 0000010D						
				810			
				811	VRR_I	VCVB, 9, 0	
00001548				812+	DS	0FD	
00001548		00001548		813+	USING	*, R5	base for test data and test routine
00001548	00001564			814+T12	DC	A(X12)	address of test routine
0000154C	000C			815+	DC	H' 12'	test number
0000154E	00			816+	DC	XL1' 00'	
0000154F	09			817+	DC	HL1' 9'	&MB
00001550	00			818+	DC	HL1' 0'	cc
00001551	07			819+	DC	HL1' 7'	cc failed mask
00001552	E5C3E5C2 40404040			820+	DC	CL8' VCVB'	instruction name
0000155C	00000010			821+	DC	A(16)	result length
00001560	00001588			822+REA12	DC	A(RE12)	result address
				823+*			INSTRUCTION UNDER TEST ROUTINE
00001564				824+X12	DS	0F	
00001564	E310 8EE0 0004		000010E0	825+	LG	R1, R1FUDGE	pollute R1
0000156A	E710 5048 0006		00001590	826+	VL	V1, RE12+8	get V1 source
00001570	E611 0090 0050			827+	VCVB	R1, V1, 9	test instruction



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001630	5020 8ED4		000010D4	882+	ST	R2, CCPSW	to save CC
00001634	07FB			883+	BR	R11	return
00001638				884+RE14	DC	0F	
00001638				885+	DROP	R5	
00001638	AABBCCDD 7FFFFFFF			886	DC	XL08' AABBCCDD7FFFFFFF'	R1 result
00001640	00000000 00000000			887	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001648	00000214 7483647C						
				888			
				889	VRR_I	VCVB, 9, 3	INT_MIN
00001650				890+	DS	0FD	
00001650		00001650		891+	USING	*, R5	base for test data and test routine
00001650	0000166C			892+T15	DC	A(X15)	address of test routine
00001654	000F			893+	DC	H' 15'	test number
00001656	00			894+	DC	XL1' 00'	
00001657	09			895+	DC	HL1' 9'	&MB
00001658	03			896+	DC	HL1' 3'	cc
00001659	0E			897+	DC	HL1' 14'	cc failed mask
0000165A	E5C3E5C2 40404040			898+	DC	CL8' VCVB'	instruction name
00001664	00000010			899+	DC	A(16)	result length
00001668	00001690			900+REA15	DC	A(RE15)	result address
				901+*			INSTRUCTION UNDER TEST ROUTINE
0000166C				902+X15	DS	0F	
0000166C	E310 8EE0 0004		000010E0	903+	LG	R1, R1FUDGE	pollute R1
00001672	E710 5048 0006		00001698	904+	VL	V1, RE15+8	get V1 source
00001678	E611 0090 0050			905+	VCVB	R1, V1, 9	test instruction
0000167E	E310 8F18 0024		00001118	906+	STG	R1, R10UTPUT	save
00001684	B98D 0020			907+	EPSW	R2, R0	exptract psw
00001688	5020 8ED4		000010D4	908+	ST	R2, CCPSW	to save CC
0000168C	07FB			909+	BR	R11	return
00001690				910+RE15	DC	0F	
00001690				911+	DROP	R5	
00001690	AABBCCDD 80000000			912	DC	XL08' AABBCCDD80000000'	R1 result
00001698	00000000 00000000			913	DC	XL16' 000000000000000000000002147483648D'	V1 source
000016A0	00000214 7483648D						
				914			
				915	VRR_I	VCVB, 11, 0	UINT_MAX
000016A8				916+	DS	0FD	
000016A8		000016A8		917+	USING	*, R5	base for test data and test routine
000016A8	000016C4			918+T16	DC	A(X16)	address of test routine
000016AC	0010			919+	DC	H' 16'	test number
000016AE	00			920+	DC	XL1' 00'	
000016AF	0B			921+	DC	HL1' 11'	&MB
000016B0	00			922+	DC	HL1' 0'	cc
000016B1	07			923+	DC	HL1' 7'	cc failed mask
000016B2	E5C3E5C2 40404040			924+	DC	CL8' VCVB'	instruction name
000016BC	00000010			925+	DC	A(16)	result length
000016C0	000016E8			926+REA16	DC	A(RE16)	result address
				927+*			INSTRUCTION UNDER TEST ROUTINE
000016C4				928+X16	DS	0F	
000016C4	E310 8EE0 0004		000010E0	929+	LG	R1, R1FUDGE	pollute R1
000016CA	E710 5048 0006		000016F0	930+	VL	V1, RE16+8	get V1 source
000016D0	E611 00B0 0050			931+	VCVB	R1, V1, 11	test instruction
000016D6	E310 8F18 0024		00001118	932+	STG	R1, R10UTPUT	save
000016DC	B98D 0020			933+	EPSW	R2, R0	exptract psw
000016E0	5020 8ED4		000010D4	934+	ST	R2, CCPSW	to save CC
000016E4	07FB			935+	BR	R11	return



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016E8				936+RE16	DC	0F	
000016E8				937+	DROP	R5	
000016E8	AABBCCDD FFFFFFFF			938	DC	XL08' AABBCCDDFFFFFFFF'	R1 result
000016F0	00000000 00000000			939	DC	XL16' 0000000000000000000000004294967295C'	V1 source
000016F8	00000429 4967295C						
				940			
				941	VRR_I	VCVB, 11, 3	UINT_MAX +1
00001700				942+	DS	0FD	
00001700		00001700		943+	USING	*, R5	base for test data and test routine
00001700	0000171C			944+T17	DC	A(X17)	address of test routine
00001704	0011			945+	DC	H' 17'	test number
00001706	00			946+	DC	XL1' 00'	
00001707	0B			947+	DC	HL1' 11'	&MB
00001708	03			948+	DC	HL1' 3'	cc
00001709	0E			949+	DC	HL1' 14'	cc failed mask
0000170A	E5C3E5C2 40404040			950+	DC	CL8' VCVB'	instruction name
00001714	00000010			951+	DC	A(16)	result length
00001718	00001740			952+REA17	DC	A(RE17)	result address
				953+*			INSTRUCTION UNDER TEST ROUTINE
0000171C				954+X17	DS	0F	
0000171C	E310 8EE0 0004		000010E0	955+	LG	R1, R1FUDGE	pollute R1
00001722	E710 5048 0006		00001748	956+	VL	V1, RE17+8	get V1 source
00001728	E611 00B0 0050			957+	VCVB	R1, V1, 11	test instruction
0000172E	E310 8F18 0024		00001118	958+	STG	R1, R10UTPUT	save
00001734	B98D 0020			959+	EPSW	R2, R0	exptract psw
00001738	5020 8ED4		000010D4	960+	ST	R2, CCPSW	to save CC
0000173C	07FB			961+	BR	R11	return
00001740				962+RE17	DC	0F	
00001740				963+	DROP	R5	
00001740	AABBCCDD 00000000			964	DC	XL08' AABBCCDD00000000'	R1 result
00001748	00000000 00000000			965	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001750	00000429 4967296C						
				966			
				967	VRR_I	VCVB, 9, 3	
00001758				968+	DS	0FD	
00001758		00001758		969+	USING	*, R5	base for test data and test routine
00001758	00001774			970+T18	DC	A(X18)	address of test routine
0000175C	0012			971+	DC	H' 18'	test number
0000175E	00			972+	DC	XL1' 00'	
0000175F	09			973+	DC	HL1' 9'	&MB
00001760	03			974+	DC	HL1' 3'	cc
00001761	0E			975+	DC	HL1' 14'	cc failed mask
00001762	E5C3E5C2 40404040			976+	DC	CL8' VCVB'	instruction name
0000176C	00000010			977+	DC	A(16)	result length
00001770	00001798			978+REA18	DC	A(RE18)	result address
				979+*			INSTRUCTION UNDER TEST ROUTINE
00001774				980+X18	DS	0F	
00001774	E310 8EE0 0004		000010E0	981+	LG	R1, R1FUDGE	pollute R1
0000177A	E710 5048 0006		000017A0	982+	VL	V1, RE18+8	get V1 source
00001780	E611 0090 0050			983+	VCVB	R1, V1, 9	test instruction
00001786	E310 8F18 0024		00001118	984+	STG	R1, R10UTPUT	save
0000178C	B98D 0020			985+	EPSW	R2, R0	exptract psw
00001790	5020 8ED4		000010D4	986+	ST	R2, CCPSW	to save CC
00001794	07FB			987+	BR	R11	return
00001798				988+RE18	DC	0F	
00001798				989+	DROP	R5	



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001848				1044+RE20	DC	0F	
00001848				1045+	DROP	R5	
00001848	FFFFFFFF FFFFFFFF6			1046	DC	XL08' FFFFFFFF6'	R1 result
00001850	00000000 00000000			1047	DC	XL16' 000000000000000000000000000010D'	V1 source
00001858	00000000 0000010D						
				1048			
				1049	VRR_I	VCVBG, 1, 0	
00001860				1050+	DS	0FD	
00001860		00001860		1051+	USING	*, R5	base for test data and test routine
00001860	0000187C			1052+T21	DC	A(X21)	address of test routine
00001864	0015			1053+	DC	H' 21'	test number
00001866	00			1054+	DC	XL1' 00'	
00001867	01			1055+	DC	HL1' 1'	&MB
00001868	00			1056+	DC	HL1' 0'	cc
00001869	07			1057+	DC	HL1' 7'	cc failed mask
0000186A	E5C3E5C2 C7404040			1058+	DC	CL8' VCVBG'	instruction name
00001874	00000010			1059+	DC	A(16)	result length
00001878	000018A0			1060+REA21	DC	A(RE21)	result address
				1061+*			INSTRUCTION UNDER TEST ROUTINE
0000187C				1062+X21	DS	0F	
0000187C	E310 8EE0 0004		000010E0	1063+	LG	R1, R1FUDGE	pollute R1
00001882	E710 5048 0006		000018A8	1064+	VL	V1, RE21+8	get V1 source
00001888	E611 0010 0052			1065+	VCVBG	R1, V1, 1	test instruction
0000188E	E310 8F18 0024		00001118	1066+	STG	R1, R10UTPUT	save
00001894	B98D 0020			1067+	EPSW	R2, R0	exptract psw
00001898	5020 8ED4		000010D4	1068+	ST	R2, CCPSW	to save CC
0000189C	07FB			1069+	BR	R11	return
000018A0				1070+RE21	DC	0F	
000018A0				1071+	DROP	R5	
000018A0	00000000 0008A160			1072	DC	XL08' 000000000008A160'	R1 result
000018A8	00000000 00000000			1073	DC	XL16' 0000000000000000000000000565600C'	V1 source
000018B0	00000000 0565600C						
				1074			
				1075	VRR_I	VCVBG, 1, 0	
000018B8				1076+	DS	0FD	
000018B8		000018B8		1077+	USING	*, R5	base for test data and test routine
000018B8	000018D4			1078+T22	DC	A(X22)	address of test routine
000018BC	0016			1079+	DC	H' 22'	test number
000018BE	00			1080+	DC	XL1' 00'	
000018BF	01			1081+	DC	HL1' 1'	&MB
000018C0	00			1082+	DC	HL1' 0'	cc
000018C1	07			1083+	DC	HL1' 7'	cc failed mask
000018C2	E5C3E5C2 C7404040			1084+	DC	CL8' VCVBG'	instruction name
000018CC	00000010			1085+	DC	A(16)	result length
000018D0	000018F8			1086+REA22	DC	A(RE22)	result address
				1087+*			INSTRUCTION UNDER TEST ROUTINE
000018D4				1088+X22	DS	0F	
000018D4	E310 8EE0 0004		000010E0	1089+	LG	R1, R1FUDGE	pollute R1
000018DA	E710 5048 0006		00001900	1090+	VL	V1, RE22+8	get V1 source
000018E0	E611 0010 0052			1091+	VCVBG	R1, V1, 1	test instruction
000018E6	E310 8F18 0024		00001118	1092+	STG	R1, R10UTPUT	save
000018EC	B98D 0020			1093+	EPSW	R2, R0	exptract psw
000018F0	5020 8ED4		000010D4	1094+	ST	R2, CCPSW	to save CC
000018F4	07FB			1095+	BR	R11	return
000018F8				1096+RE22	DC	0F	
000018F8				1097+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000018F8	FFFFFFFF FFF75EA0			1098	DC	XL08' FFFFFFFFFF75EA0'	R1 result
00001900	00000000 00000000			1099	DC	XL16' 0000000000000000000000000565600D'	V1 source
00001908	00000000 0565600D						
				1100			
				1101	VRR_I	VCVBG, 1, 0	INT_MAX
00001910				1102+	DS	OFD	
00001910		00001910		1103+	USING	*, R5	base for test data and test routine
00001910	0000192C			1104+T23	DC	A(X23)	address of test routine
00001914	0017			1105+	DC	H' 23'	test number
00001916	00			1106+	DC	XL1' 00'	
00001917	01			1107+	DC	HL1' 1'	&MB
00001918	00			1108+	DC	HL1' 0'	cc
00001919	07			1109+	DC	HL1' 7'	cc failed mask
0000191A	E5C3E5C2 C7404040			1110+	DC	CL8' VCVBG'	instruction name
00001924	00000010			1111+	DC	A(16)	result length
00001928	00001950			1112+REA23	DC	A(RE23)	result address
				1113+*			INSTRUCTION UNDER TEST ROUTINE
0000192C				1114+X23	DS	OF	
0000192C	E310 8EE0 0004		000010E0	1115+	LG	R1, R1FUDGE	pollute R1
00001932	E710 5048 0006		00001958	1116+	VL	V1, RE23+8	get V1 source
00001938	E611 0010 0052			1117+	VCVBG	R1, V1, 1	test instruction
0000193E	E310 8F18 0024		00001118	1118+	STG	R1, R10UTPUT	save
00001944	B98D 0020			1119+	EPSW	R2, R0	exptract psw
00001948	5020 8ED4		000010D4	1120+	ST	R2, CCPSW	to save CC
0000194C	07FB			1121+	BR	R11	return
00001950				1122+RE23	DC	OF	
00001950				1123+	DROP	R5	
00001950	00000000 7FFFFFFF			1124	DC	XL08' 000000007FFFFFFF'	R1 result
00001958	00000000 00000000			1125	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001960	00000214 7483647C						
				1126			
				1127	VRR_I	VCVBG, 1, 0	INT_MIN
00001968				1128+	DS	OFD	
00001968		00001968		1129+	USING	*, R5	base for test data and test routine
00001968	00001984			1130+T24	DC	A(X24)	address of test routine
0000196C	0018			1131+	DC	H' 24'	test number
0000196E	00			1132+	DC	XL1' 00'	
0000196F	01			1133+	DC	HL1' 1'	&MB
00001970	00			1134+	DC	HL1' 0'	cc
00001971	07			1135+	DC	HL1' 7'	cc failed mask
00001972	E5C3E5C2 C7404040			1136+	DC	CL8' VCVBG'	instruction name
0000197C	00000010			1137+	DC	A(16)	result length
00001980	000019A8			1138+REA24	DC	A(RE24)	result address
				1139+*			INSTRUCTION UNDER TEST ROUTINE
00001984				1140+X24	DS	OF	
00001984	E310 8EE0 0004		000010E0	1141+	LG	R1, R1FUDGE	pollute R1
0000198A	E710 5048 0006		000019B0	1142+	VL	V1, RE24+8	get V1 source
00001990	E611 0010 0052			1143+	VCVBG	R1, V1, 1	test instruction
00001996	E310 8F18 0024		00001118	1144+	STG	R1, R10UTPUT	save
0000199C	B98D 0020			1145+	EPSW	R2, R0	exptract psw
000019A0	5020 8ED4		000010D4	1146+	ST	R2, CCPSW	to save CC
000019A4	07FB			1147+	BR	R11	return
000019A8				1148+RE24	DC	OF	
000019A8				1149+	DROP	R5	
000019A8	FFFFFFFF 80000000			1150	DC	XL08' FFFFFFFFFF80000000'	R1 result
000019B0	00000000 00000000			1151	DC	XL16' 000000000000000000000002147483648D'	V1 source



LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000019B8	00000214 7483648D			1152		
				1153	VRR_I VCVBG, 1, 0	UINT_MAX
000019C0				1154+	DS OFD	
000019C0		000019C0		1155+	USING *, R5	base for test data and test routine
000019C0	000019DC			1156+T25	DC A(X25)	address of test routine
000019C4	0019			1157+	DC H' 25'	test number
000019C6	00			1158+	DC XL1' 00'	
000019C7	01			1159+	DC HL1' 1'	&MB
000019C8	00			1160+	DC HL1' 0'	cc
000019C9	07			1161+	DC HL1' 7'	cc failed mask
000019CA	E5C3E5C2 C7404040			1162+	DC CL8' VCVBG'	instruction name
000019D4	00000010			1163+	DC A(16)	result length
000019D8	00001A00			1164+REA25	DC A(RE25)	result address
				1165+*		INSTRUCTION UNDER TEST ROUTINE
000019DC				1166+X25	DS OF	
000019DC	E310 8EE0 0004		000010E0	1167+	LG R1, R1FUDGE	pollute R1
000019E2	E710 5048 0006		00001A08	1168+	VL V1, RE25+8	get V1 source
000019E8	E611 0010 0052			1169+	VCVBG R1, V1, 1	test instruction
000019EE	E310 8F18 0024		00001118	1170+	STG R1, R10UTPUT	save
000019F4	B98D 0020			1171+	EPSW R2, R0	exptract psw
000019F8	5020 8ED4		000010D4	1172+	ST R2, CCPSW	to save CC
000019FC	07FB			1173+	BR R11	return
00001A00				1174+RE25	DC OF	
00001A00				1175+	DROP R5	
00001A00	00000000 FFFFFFFF			1176	DC XL08' 00000000FFFFFFFF'	R1 result
00001A08	00000000 00000000			1177	DC XL16' 0000000000000000000000004294967295C'	V1 source
00001A10	00000429 4967295C					
				1178		
				1179	VRR_I VCVBG, 1, 0	UINT_MAX +1
00001A18				1180+	DS OFD	
00001A18		00001A18		1181+	USING *, R5	base for test data and test routine
00001A18	00001A34			1182+T26	DC A(X26)	address of test routine
00001A1C	001A			1183+	DC H' 26'	test number
00001A1E	00			1184+	DC XL1' 00'	
00001A1F	01			1185+	DC HL1' 1'	&MB
00001A20	00			1186+	DC HL1' 0'	cc
00001A21	07			1187+	DC HL1' 7'	cc failed mask
00001A22	E5C3E5C2 C7404040			1188+	DC CL8' VCVBG'	instruction name
00001A2C	00000010			1189+	DC A(16)	result length
00001A30	00001A58			1190+REA26	DC A(RE26)	result address
				1191+*		INSTRUCTION UNDER TEST ROUTINE
00001A34				1192+X26	DS OF	
00001A34	E310 8EE0 0004		000010E0	1193+	LG R1, R1FUDGE	pollute R1
00001A3A	E710 5048 0006		00001A60	1194+	VL V1, RE26+8	get V1 source
00001A40	E611 0010 0052			1195+	VCVBG R1, V1, 1	test instruction
00001A46	E310 8F18 0024		00001118	1196+	STG R1, R10UTPUT	save
00001A4C	B98D 0020			1197+	EPSW R2, R0	exptract psw
00001A50	5020 8ED4		000010D4	1198+	ST R2, CCPSW	to save CC
00001A54	07FB			1199+	BR R11	return
00001A58				1200+RE26	DC OF	
00001A58				1201+	DROP R5	
00001A58	00000001 00000000			1202	DC XL08' 0000000100000000'	R1 result
00001A60	00000000 00000000			1203	DC XL16' 0000000000000000000000004294967296C'	V1 source
00001A68	00000429 4967296C					
				1204		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001A70				1205	VRR_I	VCVBG, 1, 0	
00001A70				1206+	DS	OFD	
00001A70		00001A70		1207+	USING	*, R5	base for test data and test routine
00001A70	00001A8C			1208+T27	DC	A(X27)	address of test routine
00001A74	001B			1209+	DC	H' 27'	test number
00001A76	00			1210+	DC	XL1' 00'	
00001A77	01			1211+	DC	HL1' 1'	&MB
00001A78	00			1212+	DC	HL1' 0'	cc
00001A79	07			1213+	DC	HL1' 7'	cc failed mask
00001A7A	E5C3E5C2 C7404040			1214+	DC	CL8' VCVBG'	instruction name
00001A84	00000010			1215+	DC	A(16)	result length
00001A88	00001AB0			1216+REA27	DC	A(RE27)	result address
				1217+*			INSTRUCTION UNDER TEST ROUTINE
00001A8C				1218+X27	DS	OF	
00001A8C	E310 8EE0 0004		000010E0	1219+	LG	R1, R1FUDGE	pollute R1
00001A92	E710 5048 0006		00001AB8	1220+	VL	V1, RE27+8	get V1 source
00001A98	E611 0010 0052			1221+	VCVBG	R1, V1, 1	test instruction
00001A9E	E310 8F18 0024		00001118	1222+	STG	R1, R10UTPUT	save
00001AA4	B98D 0020			1223+	EPSW	R2, R0	exptract psw
00001AA8	5020 8ED4		000010D4	1224+	ST	R2, CCPSW	to save CC
00001AAC	07FB			1225+	BR	R11	return
00001AB0				1226+RE27	DC	OF	
00001AB0				1227+	DROP	R5	
00001AB0	00000002 DF8E1660			1228	DC	XL08' 00000002DF8E1660'	R1 result
00001AB8	00000000 00000000			1229	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001AC0	00001234 0565600C						
				1230			
00001AC8				1231	VRR_I	VCVBG, 1, 0	LONG_MAX
00001AC8		00001AC8		1232+	DS	OFD	
00001AC8	00001AE4			1233+	USING	*, R5	base for test data and test routine
00001ACC	001C			1234+T28	DC	A(X28)	address of test routine
00001ACE	00			1235+	DC	H' 28'	test number
00001ACF	01			1236+	DC	XL1' 00'	
00001AD0	00			1237+	DC	HL1' 1'	&MB
00001AD1	07			1238+	DC	HL1' 0'	cc
00001AD2	E5C3E5C2 C7404040			1239+	DC	HL1' 7'	cc failed mask
00001AD2	E5C3E5C2 C7404040			1240+	DC	CL8' VCVBG'	instruction name
00001ADC	00000010			1241+	DC	A(16)	result length
00001AE0	00001B08			1242+REA28	DC	A(RE28)	result address
				1243+*			INSTRUCTION UNDER TEST ROUTINE
00001AE4				1244+X28	DS	OF	
00001AE4	E310 8EE0 0004		000010E0	1245+	LG	R1, R1FUDGE	pollute R1
00001AEA	E710 5048 0006		00001B10	1246+	VL	V1, RE28+8	get V1 source
00001AF0	E611 0010 0052			1247+	VCVBG	R1, V1, 1	test instruction
00001AF6	E310 8F18 0024		00001118	1248+	STG	R1, R10UTPUT	save
00001AFC	B98D 0020			1249+	EPSW	R2, R0	exptract psw
00001B00	5020 8ED4		000010D4	1250+	ST	R2, CCPSW	to save CC
00001B04	07FB			1251+	BR	R11	return
00001B08				1252+RE28	DC	OF	
00001B08				1253+	DROP	R5	
00001B08	7FFFFFFF FFFFFFFF			1254	DC	XL08' 7FFFFFFF7FFFFFFF'	R1 result
00001B10	00000000 00009223			1255	DC	XL16' 000000000000009223372036854775807C'	V1 source
00001B18	37203685 4775807C						
				1256			
00001B20				1257	VRR_I	VCVBG, 1, 0	LONG_MIN
				1258+	DS	OFD	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001B20		00001B20		1259+	USING *, R5	base for test data and test routine
00001B20	00001B3C			1260+T29	DC A(X29)	address of test routine
00001B24	001D			1261+	DC H' 29'	test number
00001B26	00			1262+	DC XL1' 00'	
00001B27	01			1263+	DC HL1' 1'	&MB
00001B28	00			1264+	DC HL1' 0'	cc
00001B29	07			1265+	DC HL1' 7'	cc failed mask
00001B2A	E5C3E5C2 C7404040			1266+	DC CL8' VCVBG'	instruction name
00001B34	00000010			1267+	DC A(16)	result length
00001B38	00001B60			1268+REA29	DC A(RE29)	result address
				1269+*		INSTRUCTION UNDER TEST ROUTINE
00001B3C				1270+X29	DS 0F	
00001B3C	E310 8EE0 0004		000010E0	1271+	LG R1, R1FUDGE	pollute R1
00001B42	E710 5048 0006		00001B68	1272+	VL V1, RE29+8	get V1 source
00001B48	E611 0010 0052			1273+	VCVBG R1, V1, 1	test instruction
00001B4E	E310 8F18 0024		00001118	1274+	STG R1, R10UTPUT	save
00001B54	B98D 0020			1275+	EPSW R2, R0	exptract psw
00001B58	5020 8ED4		000010D4	1276+	ST R2, CCPSW	to save CC
00001B5C	07FB			1277+	BR R11	return
00001B60				1278+RE29	DC 0F	
00001B60				1279+	DROP R5	
00001B60	80000000 00000000			1280	DC XL08' 8000000000000000'	R1 result
00001B68	00000000 00009223			1281	DC XL16' 0000000000009223372036854775808D'	V1 source
00001B70	37203685 4775808D					
				1282		
				1283	VRR_I VCVBG, 3, 0	ULONG_MAX
00001B78				1284+	DS 0FD	
00001B78		00001B78		1285+	USING *, R5	base for test data and test routine
00001B78	00001B94			1286+T30	DC A(X30)	address of test routine
00001B7C	001E			1287+	DC H' 30'	test number
00001B7E	00			1288+	DC XL1' 00'	
00001B7F	03			1289+	DC HL1' 3'	&MB
00001B80	00			1290+	DC HL1' 0'	cc
00001B81	07			1291+	DC HL1' 7'	cc failed mask
00001B82	E5C3E5C2 C7404040			1292+	DC CL8' VCVBG'	instruction name
00001B8C	00000010			1293+	DC A(16)	result length
00001B90	00001BB8			1294+REA30	DC A(RE30)	result address
				1295+*		INSTRUCTION UNDER TEST ROUTINE
00001B94				1296+X30	DS 0F	
00001B94	E310 8EE0 0004		000010E0	1297+	LG R1, R1FUDGE	pollute R1
00001B9A	E710 5048 0006		00001BC0	1298+	VL V1, RE30+8	get V1 source
00001BA0	E611 0030 0052			1299+	VCVBG R1, V1, 3	test instruction
00001BA6	E310 8F18 0024		00001118	1300+	STG R1, R10UTPUT	save
00001BAC	B98D 0020			1301+	EPSW R2, R0	exptract psw
00001BB0	5020 8ED4		000010D4	1302+	ST R2, CCPSW	to save CC
00001BB4	07FB			1303+	BR R11	return
00001BB8				1304+RE30	DC 0F	
00001BB8				1305+	DROP R5	
00001BB8	FFFFFFFF FFFFFFFF			1306	DC XL08' FFFFFFFFFFFFFFFFFF'	R1 result
00001BC0	00000000 00018446			1307	DC XL16' 0000000000018446744073709551615C'	V1 source
00001BC8	74407370 9551615C					
				1308		
				1309	VRR_I VCVBG, 3, 3	ULONG_MAX +1
00001BD0				1310+	DS 0FD	
00001BD0		00001BD0		1311+	USING *, R5	base for test data and test routine
00001BD0	00001BEC			1312+T31	DC A(X31)	address of test routine



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001BD4	001F			1313+	DC	H' 31'	test number
00001BD6	00			1314+	DC	XL1' 00'	
00001BD7	03			1315+	DC	HL1' 3'	&MB
00001BD8	03			1316+	DC	HL1' 3'	cc
00001BD9	0E			1317+	DC	HL1' 14'	cc failed mask
00001BDA	E5C3E5C2 C7404040			1318+	DC	CL8' VCVBG'	instruction name
00001BE4	00000010			1319+	DC	A(16)	result length
00001BE8	00001C10			1320+REA31	DC	A(RE31)	result address
				1321+*			INSTRUCTION UNDER TEST ROUTINE
00001BEC				1322+X31	DS	0F	
00001BEC	E310 8EE0 0004		000010E0	1323+	LG	R1, R1FUDGE	pollute R1
00001BF2	E710 5048 0006		00001C18	1324+	VL	V1, RE31+8	get V1 source
00001BF8	E611 0030 0052			1325+	VCVBG	R1, V1, 3	test instruction
00001BFE	E310 8F18 0024		00001118	1326+	STG	R1, R10UTPUT	save
00001C04	B98D 0020			1327+	EPSW	R2, R0	exptract psw
00001C08	5020 8ED4		000010D4	1328+	ST	R2, CCPSW	to save CC
00001C0C	07FB			1329+	BR	R11	return
00001C10				1330+RE31	DC	0F	
00001C10				1331+	DROP	R5	
00001C10	00000000 00000000			1332	DC	XL08' 00000000000000000'	R1 result
00001C18	00000000 00018446			1333	DC	XL16' 0000000000018446744073709551616C'	V1 source
00001C20	74407370 9551616C						
				1334			
				1335	VRR_I	VCVBG, 3, 3	ULONG_MAX +11
00001C28				1336+	DS	0FD	
00001C28		00001C28		1337+	USING	*, R5	base for test data and test routine
00001C28	00001C44			1338+T32	DC	A(X32)	address of test routine
00001C2C	0020			1339+	DC	H' 32'	test number
00001C2E	00			1340+	DC	XL1' 00'	
00001C2F	03			1341+	DC	HL1' 3'	&MB
00001C30	03			1342+	DC	HL1' 3'	cc
00001C31	0E			1343+	DC	HL1' 14'	cc failed mask
00001C32	E5C3E5C2 C7404040			1344+	DC	CL8' VCVBG'	instruction name
00001C3C	00000010			1345+	DC	A(16)	result length
00001C40	00001C68			1346+REA32	DC	A(RE32)	result address
				1347+*			INSTRUCTION UNDER TEST ROUTINE
00001C44				1348+X32	DS	0F	
00001C44	E310 8EE0 0004		000010E0	1349+	LG	R1, R1FUDGE	pollute R1
00001C4A	E710 5048 0006		00001C70	1350+	VL	V1, RE32+8	get V1 source
00001C50	E611 0030 0052			1351+	VCVBG	R1, V1, 3	test instruction
00001C56	E310 8F18 0024		00001118	1352+	STG	R1, R10UTPUT	save
00001C5C	B98D 0020			1353+	EPSW	R2, R0	exptract psw
00001C60	5020 8ED4		000010D4	1354+	ST	R2, CCPSW	to save CC
00001C64	07FB			1355+	BR	R11	return
00001C68				1356+RE32	DC	0F	
00001C68				1357+	DROP	R5	
00001C68	00000000 0000000A			1358	DC	XL08' 0000000000000000A'	R1 result
00001C70	00000000 00018446			1359	DC	XL16' 0000000000018446744073709551626C'	V1 source
00001C78	74407370 9551626C						
				1360			
				1361 * VCVBG simple: p2=1			
				1362	VRR_I	VCVBG, 9, 0	
00001C80				1363+	DS	0FD	
00001C80		00001C80		1364+	USING	*, R5	base for test data and test routine
00001C80	00001C9C			1365+T33	DC	A(X33)	address of test routine
00001C84	0021			1366+	DC	H' 33'	test number

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C86	00			1367+	DC	XL1' 00'	
00001C87	09			1368+	DC	HL1' 9'	&MB
00001C88	00			1369+	DC	HL1' 0'	cc
00001C89	07			1370+	DC	HL1' 7'	cc failed mask
00001C8A	E5C3E5C2 C7404040			1371+	DC	CL8' VCVBG'	instruction name
00001C94	00000010			1372+	DC	A(16)	result length
00001C98	00001CC0			1373+REA33	DC	A(RE33)	result address
				1374+*			INSTRUCTION UNDER TEST ROUTINE
00001C9C				1375+X33	DS	0F	
00001C9C	E310 8EE0 0004		000010E0	1376+	LG	R1, R1FUDGE	pollute R1
00001CA2	E710 5048 0006		00001CC8	1377+	VL	V1, RE33+8	get V1 source
00001CA8	E611 0090 0052			1378+	VCVBG	R1, V1, 9	test instruction
00001CAE	E310 8F18 0024		00001118	1379+	STG	R1, R10UTPUT	save
00001CB4	B98D 0020			1380+	EPSW	R2, R0	exptract psw
00001CB8	5020 8ED4		000010D4	1381+	ST	R2, CCPSW	to save CC
00001CBC	07FB			1382+	BR	R11	return
00001CC0				1383+RE33	DC	0F	
00001CC0				1384+	DROP	R5	
00001CC0	00000000 0000000A			1385	DC	XL08' 0000000000000000A'	R1 result
00001CC8	00000000 00000000			1386	DC	XL16' 0000000000000000000000000000000010C'	V1 source
00001CD0	00000000 0000010C						
				1387			
				1388	VRR_I	VCVBG, 9, 0	
00001CD8				1389+	DS	0FD	
00001CD8		00001CD8		1390+	USING	*, R5	base for test data and test routine
00001CD8	00001CF4			1391+T34	DC	A(X34)	address of test routine
00001CDC	0022			1392+	DC	H' 34'	test number
00001CDE	00			1393+	DC	XL1' 00'	
00001CDF	09			1394+	DC	HL1' 9'	&MB
00001CE0	00			1395+	DC	HL1' 0'	cc
00001CE1	07			1396+	DC	HL1' 7'	cc failed mask
00001CE2	E5C3E5C2 C7404040			1397+	DC	CL8' VCVBG'	instruction name
00001CEC	00000010			1398+	DC	A(16)	result length
00001CF0	00001D18			1399+REA34	DC	A(RE34)	result address
				1400+*			INSTRUCTION UNDER TEST ROUTINE
00001CF4				1401+X34	DS	0F	
00001CF4	E310 8EE0 0004		000010E0	1402+	LG	R1, R1FUDGE	pollute R1
00001CFA	E710 5048 0006		00001D20	1403+	VL	V1, RE34+8	get V1 source
00001D00	E611 0090 0052			1404+	VCVBG	R1, V1, 9	test instruction
00001D06	E310 8F18 0024		00001118	1405+	STG	R1, R10UTPUT	save
00001D0C	B98D 0020			1406+	EPSW	R2, R0	exptract psw
00001D10	5020 8ED4		000010D4	1407+	ST	R2, CCPSW	to save CC
00001D14	07FB			1408+	BR	R11	return
00001D18				1409+RE34	DC	0F	
00001D18				1410+	DROP	R5	
00001D18	00000000 0000000A			1411	DC	XL08' 0000000000000000A'	R1 result
00001D20	00000000 00000000			1412	DC	XL16' 000000000000000000000000000010D'	V1 source
00001D28	00000000 0000010D						
				1413			
				1414	VRR_I	VCVBG, 9, 0	
00001D30				1415+	DS	0FD	
00001D30		00001D30		1416+	USING	*, R5	base for test data and test routine
00001D30	00001D4C			1417+T35	DC	A(X35)	address of test routine
00001D34	0023			1418+	DC	H' 35'	test number
00001D36	00			1419+	DC	XL1' 00'	
00001D37	09			1420+	DC	HL1' 9'	&MB

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D38	00			1421+	DC	HL1' 0'	cc
00001D39	07			1422+	DC	HL1' 7'	cc failed mask
00001D3A	E5C3E5C2 C7404040			1423+	DC	CL8' VCVBG'	instruction name
00001D44	00000010			1424+	DC	A(16)	result length
00001D48	00001D70			1425+REA35	DC	A(RE35)	result address
				1426+*			INSTRUCTION UNDER TEST ROUTINE
00001D4C				1427+X35	DS	OF	
00001D4C	E310 8EE0 0004		000010E0	1428+	LG	R1, R1FUDGE	pollute R1
00001D52	E710 5048 0006		00001D78	1429+	VL	V1, RE35+8	get V1 source
00001D58	E611 0090 0052			1430+	VCVBG	R1, V1, 9	test instruction
00001D5E	E310 8F18 0024		00001118	1431+	STG	R1, R10UTPUT	save
00001D64	B98D 0020			1432+	EPSW	R2, R0	exptract psw
00001D68	5020 8ED4		000010D4	1433+	ST	R2, CCPSW	to save CC
00001D6C	07FB			1434+	BR	R11	return
00001D70				1435+RE35	DC	OF	
00001D70				1436+	DROP	R5	
00001D70	00000000 0008A160			1437	DC	XL08' 0000000000008A160'	R1 result
00001D78	00000000 00000000			1438	DC	XL16' 0000000000000000000000000565600C'	V1 source
00001D80	00000000 0565600C						
				1439			
				1440	VRR_I	VCVBG, 9, 0	
00001D88				1441+	DS	OFD	
00001D88		00001D88		1442+	USING	*, R5	base for test data and test routine
00001D88	00001DA4			1443+T36	DC	A(X36)	address of test routine
00001D8C	0024			1444+	DC	H' 36'	test number
00001D8E	00			1445+	DC	XL1' 00'	
00001D8F	09			1446+	DC	HL1' 9'	&MB
00001D90	00			1447+	DC	HL1' 0'	cc
00001D91	07			1448+	DC	HL1' 7'	cc failed mask
00001D92	E5C3E5C2 C7404040			1449+	DC	CL8' VCVBG'	instruction name
00001D9C	00000010			1450+	DC	A(16)	result length
00001DA0	00001DC8			1451+REA36	DC	A(RE36)	result address
				1452+*			INSTRUCTION UNDER TEST ROUTINE
00001DA4				1453+X36	DS	OF	
00001DA4	E310 8EE0 0004		000010E0	1454+	LG	R1, R1FUDGE	pollute R1
00001DAA	E710 5048 0006		00001DD0	1455+	VL	V1, RE36+8	get V1 source
00001DB0	E611 0090 0052			1456+	VCVBG	R1, V1, 9	test instruction
00001DB6	E310 8F18 0024		00001118	1457+	STG	R1, R10UTPUT	save
00001DBC	B98D 0020			1458+	EPSW	R2, R0	exptract psw
00001DC0	5020 8ED4		000010D4	1459+	ST	R2, CCPSW	to save CC
00001DC4	07FB			1460+	BR	R11	return
00001DC8				1461+RE36	DC	OF	
00001DC8				1462+	DROP	R5	
00001DC8	00000000 0008A160			1463	DC	XL08' 0000000000008A160'	R1 result
00001DD0	00000000 00000000			1464	DC	XL16' 0000000000000000000000000565600D'	V1 source
00001DD8	00000000 0565600D						
				1465			
				1466	VRR_I	VCVBG, 9, 0	INT_MAX
00001DE0				1467+	DS	OFD	
00001DE0		00001DE0		1468+	USING	*, R5	base for test data and test routine
00001DE0	00001DFC			1469+T37	DC	A(X37)	address of test routine
00001DE4	0025			1470+	DC	H' 37'	test number
00001DE6	00			1471+	DC	XL1' 00'	
00001DE7	09			1472+	DC	HL1' 9'	&MB
00001DE8	00			1473+	DC	HL1' 0'	cc
00001DE9	07			1474+	DC	HL1' 7'	cc failed mask

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001DEA	E5C3E5C2 C7404040			1475+	DC	CL8' VCVBG'	instruction name
00001DF4	00000010			1476+	DC	A(16)	result length
00001DF8	00001E20			1477+REA37	DC	A(RE37)	result address
				1478+*			INSTRUCTION UNDER TEST ROUTINE
00001DFC				1479+X37	DS	OF	
00001DFC	E310 8EE0 0004		000010E0	1480+	LG	R1, R1FUDGE	pollute R1
00001E02	E710 5048 0006		00001E28	1481+	VL	V1, RE37+8	get V1 source
00001E08	E611 0090 0052			1482+	VCVBG	R1, V1, 9	test instruction
00001E0E	E310 8F18 0024		00001118	1483+	STG	R1, R10UTPUT	save
00001E14	B98D 0020			1484+	EPSW	R2, R0	exptract psw
00001E18	5020 8ED4		000010D4	1485+	ST	R2, CCPSW	to save CC
00001E1C	07FB			1486+	BR	R11	return
00001E20				1487+RE37	DC	OF	
00001E20				1488+	DROP	R5	
00001E20	00000000 7FFFFFFF			1489	DC	XL08' 000000007FFFFFFF'	R1 result
00001E28	00000000 00000000			1490	DC	XL16' 000000000000000000000002147483647C'	V1 source
00001E30	00000214 7483647C						
				1491			
				1492	VRR_I	VCVBG, 9, 0	INT_MIN
00001E38				1493+	DS	OFD	
00001E38		00001E38		1494+	USING	*, R5	base for test data and test routine
00001E38	00001E54			1495+T38	DC	A(X38)	address of test routine
00001E3C	0026			1496+	DC	H' 38'	test number
00001E3E	00			1497+	DC	XL1' 00'	
00001E3F	09			1498+	DC	HL1' 9'	&MB
00001E40	00			1499+	DC	HL1' 0'	cc
00001E41	07			1500+	DC	HL1' 7'	cc failed mask
00001E42	E5C3E5C2 C7404040			1501+	DC	CL8' VCVBG'	instruction name
00001E4C	00000010			1502+	DC	A(16)	result length
00001E50	00001E78			1503+REA38	DC	A(RE38)	result address
				1504+*			INSTRUCTION UNDER TEST ROUTINE
00001E54				1505+X38	DS	OF	
00001E54	E310 8EE0 0004		000010E0	1506+	LG	R1, R1FUDGE	pollute R1
00001E5A	E710 5048 0006		00001E80	1507+	VL	V1, RE38+8	get V1 source
00001E60	E611 0090 0052			1508+	VCVBG	R1, V1, 9	test instruction
00001E66	E310 8F18 0024		00001118	1509+	STG	R1, R10UTPUT	save
00001E6C	B98D 0020			1510+	EPSW	R2, R0	exptract psw
00001E70	5020 8ED4		000010D4	1511+	ST	R2, CCPSW	to save CC
00001E74	07FB			1512+	BR	R11	return
00001E78				1513+RE38	DC	OF	
00001E78				1514+	DROP	R5	
00001E78	00000000 80000000			1515	DC	XL08' 0000000080000000'	R1 result
00001E80	00000000 00000000			1516	DC	XL16' 000000000000000000000002147483648D'	V1 source
00001E88	00000214 7483648D						
				1517			
				1518	VRR_I	VCVBG, 9, 0	UINT_MAX
00001E90				1519+	DS	OFD	
00001E90		00001E90		1520+	USING	*, R5	base for test data and test routine
00001E90	00001EAC			1521+T39	DC	A(X39)	address of test routine
00001E94	0027			1522+	DC	H' 39'	test number
00001E96	00			1523+	DC	XL1' 00'	
00001E97	09			1524+	DC	HL1' 9'	&MB
00001E98	00			1525+	DC	HL1' 0'	cc
00001E99	07			1526+	DC	HL1' 7'	cc failed mask
00001E9A	E5C3E5C2 C7404040			1527+	DC	CL8' VCVBG'	instruction name
00001EA4	00000010			1528+	DC	A(16)	result length



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001EA8	00001ED0			1529+REA39	DC	A(RE39)	result address
				1530+*			INSTRUCTION UNDER TEST ROUTINE
00001EAC				1531+X39	DS	0F	
00001EAC	E310 8EE0 0004		000010E0	1532+	LG	R1, R1FUDGE	pollute R1
00001EB2	E710 5048 0006		00001ED8	1533+	VL	V1, RE39+8	get V1 source
00001EB8	E611 0090 0052			1534+	VCVBG	R1, V1, 9	test instruction
00001EBE	E310 8F18 0024		00001118	1535+	STG	R1, R10UTPUT	save
00001EC4	B98D 0020			1536+	EPSW	R2, R0	exptract psw
00001EC8	5020 8ED4		000010D4	1537+	ST	R2, CCPSW	to save CC
00001ECC	07FB			1538+	BR	R11	return
00001ED0				1539+RE39	DC	0F	
00001ED0				1540+	DROP	R5	
00001ED0	00000000 FFFFFFFF			1541	DC	XL08' 00000000FFFFFFFF'	R1 result
00001ED8	00000000 00000000			1542	DC	XL16' 0000000000000000000000004294967295C'	V1 source
00001EE0	00000429 4967295C						
				1543			
				1544	VRR_I	V1, 9, 0	UINT_MAX +1
00001EE8				1545+	DS	0FD	
00001EE8		00001EE8		1546+	USING	*, R5	base for test data and test routine
00001EE8	00001F04			1547+T40	DC	A(X40)	address of test routine
00001EEC	0028			1548+	DC	H' 40'	test number
00001EEE	00			1549+	DC	XL1' 00'	
00001EEF	09			1550+	DC	HL1' 9'	&MB
00001EF0	00			1551+	DC	HL1' 0'	cc
00001EF1	07			1552+	DC	HL1' 7'	cc failed mask
00001EF2	E5C3E5C2 C7404040			1553+	DC	CL8' VCVBG'	instruction name
00001EFC	00000010			1554+	DC	A(16)	result length
00001F00	00001F28			1555+REA40	DC	A(RE40)	result address
				1556+*			INSTRUCTION UNDER TEST ROUTINE
00001F04				1557+X40	DS	0F	
00001F04	E310 8EE0 0004		000010E0	1558+	LG	R1, R1FUDGE	pollute R1
00001F0A	E710 5048 0006		00001F30	1559+	VL	V1, RE40+8	get V1 source
00001F10	E611 0090 0052			1560+	VCVBG	R1, V1, 9	test instruction
00001F16	E310 8F18 0024		00001118	1561+	STG	R1, R10UTPUT	save
00001F1C	B98D 0020			1562+	EPSW	R2, R0	exptract psw
00001F20	5020 8ED4		000010D4	1563+	ST	R2, CCPSW	to save CC
00001F24	07FB			1564+	BR	R11	return
00001F28				1565+RE40	DC	0F	
00001F28				1566+	DROP	R5	
00001F28	00000001 00000000			1567	DC	XL08' 0000000100000000'	R1 result
00001F30	00000000 00000000			1568	DC	XL16' 0000000000000000000000004294967296C'	V1 source
00001F38	00000429 4967296C						
				1569			
				1570	VRR_I	V1, 9, 0	
00001F40				1571+	DS	0FD	
00001F40		00001F40		1572+	USING	*, R5	base for test data and test routine
00001F40	00001F5C			1573+T41	DC	A(X41)	address of test routine
00001F44	0029			1574+	DC	H' 41'	test number
00001F46	00			1575+	DC	XL1' 00'	
00001F47	09			1576+	DC	HL1' 9'	&MB
00001F48	00			1577+	DC	HL1' 0'	cc
00001F49	07			1578+	DC	HL1' 7'	cc failed mask
00001F4A	E5C3E5C2 C7404040			1579+	DC	CL8' VCVBG'	instruction name
00001F54	00000010			1580+	DC	A(16)	result length
00001F58	00001F80			1581+REA41	DC	A(RE41)	result address
				1582+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001F5C				1583+X41	DS	OF	
00001F5C	E310 8EE0 0004		000010E0	1584+	LG	R1, R1FUDGE	pollute R1
00001F62	E710 5048 0006		00001F88	1585+	VL	V1, RE41+8	get V1 source
00001F68	E611 0090 0052			1586+	VCVBG	R1, V1, 9	test instruction
00001F6E	E310 8F18 0024		00001118	1587+	STG	R1, R10UTPUT	save
00001F74	B98D 0020			1588+	EPSW	R2, R0	exptract psw
00001F78	5020 8ED4		000010D4	1589+	ST	R2, CCPSW	to save CC
00001F7C	07FB			1590+	BR	R11	return
00001F80				1591+RE41	DC	OF	
00001F80				1592+	DROP	R5	
00001F80	00000002 DF8E1660			1593	DC	XL08' 00000002DF8E1660'	R1 result
00001F88	00000000 00000000			1594	DC	XL16' 00000000000000000000000012340565600C'	V1 source
00001F90	00001234 0565600C						
				1595			
				1596	VRR_I	VCVBG, 9, 0	LONG_MAX
00001F98				1597+	DS	OFD	
00001F98		00001F98		1598+	USING	*, R5	base for test data and test routine
00001F98	00001FB4			1599+T42	DC	A(X42)	address of test routine
00001F9C	002A			1600+	DC	H' 42'	test number
00001F9E	00			1601+	DC	XL1' 00'	
00001F9F	09			1602+	DC	HL1' 9'	&MB
00001FA0	00			1603+	DC	HL1' 0'	cc
00001FA1	07			1604+	DC	HL1' 7'	cc failed mask
00001FA2	E5C3E5C2 C7404040			1605+	DC	CL8' VCVBG'	instruction name
00001FAC	00000010			1606+	DC	A(16)	result length
00001FB0	00001FD8			1607+REA42	DC	A(RE42)	result address
				1608+*			INSTRUCTION UNDER TEST ROUTINE
00001FB4				1609+X42	DS	OF	
00001FB4	E310 8EE0 0004		000010E0	1610+	LG	R1, R1FUDGE	pollute R1
00001FBA	E710 5048 0006		00001FE0	1611+	VL	V1, RE42+8	get V1 source
00001FC0	E611 0090 0052			1612+	VCVBG	R1, V1, 9	test instruction
00001FC6	E310 8F18 0024		00001118	1613+	STG	R1, R10UTPUT	save
00001FCC	B98D 0020			1614+	EPSW	R2, R0	exptract psw
00001FD0	5020 8ED4		000010D4	1615+	ST	R2, CCPSW	to save CC
00001FD4	07FB			1616+	BR	R11	return
00001FD8				1617+RE42	DC	OF	
00001FD8				1618+	DROP	R5	
00001FD8	7FFFFFFF FFFFFFFF			1619	DC	XL08' 7FFFFFFF7FFFFFFF'	R1 result
00001FE0	00000000 00009223			1620	DC	XL16' 0000000000009223372036854775807C'	V1 source
00001FE8	37203685 4775807C						
				1621			
				1622	VRR_I	VCVBG, 9, 0	LONG_MIN
00001FF0				1623+	DS	OFD	
00001FF0		00001FF0		1624+	USING	*, R5	base for test data and test routine
00001FF0	0000200C			1625+T43	DC	A(X43)	address of test routine
00001FF4	002B			1626+	DC	H' 43'	test number
00001FF6	00			1627+	DC	XL1' 00'	
00001FF7	09			1628+	DC	HL1' 9'	&MB
00001FF8	00			1629+	DC	HL1' 0'	cc
00001FF9	07			1630+	DC	HL1' 7'	cc failed mask
00001FFA	E5C3E5C2 C7404040			1631+	DC	CL8' VCVBG'	instruction name
00002004	00000010			1632+	DC	A(16)	result length
00002008	00002030			1633+REA43	DC	A(RE43)	result address
				1634+*			INSTRUCTION UNDER TEST ROUTINE
0000200C				1635+X43	DS	OF	
0000200C	E310 8EE0 0004		000010E0	1636+	LG	R1, R1FUDGE	pollute R1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002012	E710 5048 0006		00002038	1637+	VL	V1, RE43+8	get V1 source
00002018	E611 0090 0052			1638+	VCVBG	R1, V1, 9	test instruction
0000201E	E310 8F18 0024		00001118	1639+	STG	R1, R10UTPUT	save
00002024	B98D 0020			1640+	EPSW	R2, R0	exptract psw
00002028	5020 8ED4		000010D4	1641+	ST	R2, CCPSW	to save CC
0000202C	07FB			1642+	BR	R11	return
00002030				1643+RE43	DC	0F	
00002030				1644+	DROP	R5	
00002030	80000000 00000000			1645	DC	XL08' 8000000000000000'	R1 result
00002038	00000000 00009223			1646	DC	XL16' 0000000000009223372036854775808D'	V1 source
00002040	37203685 4775808D						
				1647			
				1648	VRR_I	VCVBG, 11, 0	ULONG_MAX
00002048				1649+	DS	0FD	
00002048		00002048		1650+	USING	*, R5	base for test data and test routine
00002048	00002064			1651+T44	DC	A(X44)	address of test routine
0000204C	002C			1652+	DC	H' 44'	test number
0000204E	00			1653+	DC	XL1' 00'	
0000204F	0B			1654+	DC	HL1' 11'	&MB
00002050	00			1655+	DC	HL1' 0'	cc
00002051	07			1656+	DC	HL1' 7'	cc failed mask
00002052	E5C3E5C2 C7404040			1657+	DC	CL8' VCVBG'	instruction name
0000205C	00000010			1658+	DC	A(16)	result length
00002060	00002088			1659+REA44	DC	A(RE44)	result address
				1660+*			INSTRUCTION UNDER TEST ROUTINE
00002064				1661+X44	DS	0F	
00002064	E310 8EE0 0004		000010E0	1662+	LG	R1, R1FUDGE	pollute R1
0000206A	E710 5048 0006		00002090	1663+	VL	V1, RE44+8	get V1 source
00002070	E611 00B0 0052			1664+	VCVBG	R1, V1, 11	test instruction
00002076	E310 8F18 0024		00001118	1665+	STG	R1, R10UTPUT	save
0000207C	B98D 0020			1666+	EPSW	R2, R0	exptract psw
00002080	5020 8ED4		000010D4	1667+	ST	R2, CCPSW	to save CC
00002084	07FB			1668+	BR	R11	return
00002088				1669+RE44	DC	0F	
00002088				1670+	DROP	R5	
00002088	FFFFFFFF FFFFFFFF			1671	DC	XL08' FFFFFFFFFFFFFFFF'	R1 result
00002090	00000000 00018446			1672	DC	XL16' 0000000000018446744073709551615C'	V1 source
00002098	74407370 9551615C						
				1673			
				1674	VRR_I	VCVBG, 11, 3	ULONG_MAX +1
000020A0				1675+	DS	0FD	
000020A0		000020A0		1676+	USING	*, R5	base for test data and test routine
000020A0	000020BC			1677+T45	DC	A(X45)	address of test routine
000020A4	002D			1678+	DC	H' 45'	test number
000020A6	00			1679+	DC	XL1' 00'	
000020A7	0B			1680+	DC	HL1' 11'	&MB
000020A8	03			1681+	DC	HL1' 3'	cc
000020A9	0E			1682+	DC	HL1' 14'	cc failed mask
000020AA	E5C3E5C2 C7404040			1683+	DC	CL8' VCVBG'	instruction name
000020B4	00000010			1684+	DC	A(16)	result length
000020B8	000020E0			1685+REA45	DC	A(RE45)	result address
				1686+*			INSTRUCTION UNDER TEST ROUTINE
000020BC				1687+X45	DS	0F	
000020BC	E310 8EE0 0004		000010E0	1688+	LG	R1, R1FUDGE	pollute R1
000020C2	E710 5048 0006		000020E8	1689+	VL	V1, RE45+8	get V1 source
000020C8	E611 00B0 0052			1690+	VCVBG	R1, V1, 11	test instruction



LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000020CE	E310 8F18 0024		00001118	1691+	STG	R1, R10OUTPUT	save
000020D4	B98D 0020			1692+	EPSW	R2, R0	exptract psw
000020D8	5020 8ED4		000010D4	1693+	ST	R2, CCPSW	to save CC
000020DC	07FB			1694+	BR	R11	return
000020E0				1695+RE45	DC	OF	
000020E0				1696+	DROP	R5	
000020E0	00000000 00000000			1697	DC	XL08' 00000000000000000'	R1 result
000020E8	00000000 00018446			1698	DC	XL16' 00000000000018446744073709551616C'	V1 source
000020F0	74407370 9551616C						
				1699			
				1700	VRR_I	VCVBG, 11, 3	ULONG_MAX +11
000020F8				1701+	DS	OFD	
000020F8		000020F8		1702+	USING	*, R5	base for test data and test routine
000020F8	00002114			1703+T46	DC	A(X46)	address of test routine
000020FC	002E			1704+	DC	H' 46'	test number
000020FE	00			1705+	DC	XL1' 00'	
000020FF	0B			1706+	DC	HL1' 11'	&MB
00002100	03			1707+	DC	HL1' 3'	cc
00002101	0E			1708+	DC	HL1' 14'	cc failed mask
00002102	E5C3E5C2 C7404040			1709+	DC	CL8' VCVBG'	instruction name
0000210C	00000010			1710+	DC	A(16)	result length
00002110	00002138			1711+REA46	DC	A(RE46)	result address
				1712+*			INSTRUCTION UNDER TEST ROUTINE
00002114				1713+X46	DS	OF	
00002114	E310 8EE0 0004		000010E0	1714+	LG	R1, R1FUDGE	pollute R1
0000211A	E710 5048 0006		00002140	1715+	VL	V1, RE46+8	get V1 source
00002120	E611 00B0 0052			1716+	VCVBG	R1, V1, 11	test instruction
00002126	E310 8F18 0024		00001118	1717+	STG	R1, R10OUTPUT	save
0000212C	B98D 0020			1718+	EPSW	R2, R0	exptract psw
00002130	5020 8ED4		000010D4	1719+	ST	R2, CCPSW	to save CC
00002134	07FB			1720+	BR	R11	return
00002138				1721+RE46	DC	OF	
00002138				1722+	DROP	R5	
00002138	00000000 0000000A			1723	DC	XL08' 0000000000000000A'	R1 result
00002140	00000000 00018446			1724	DC	XL16' 00000000000018446744073709551626C'	V1 source
00002148	74407370 9551626C						
				1725			
00002150	00000000			1726	DC	F' 0'	END OF TABLE
00002154	00000000			1727	DC	F' 0'	
				1728 *			
				1729 *	table of pointers to individual load test		
				1730 *			
00002158				1731 E6TESTS	DS	OF	
				1732	PTTABLE		
00002158				1733+TTABLE	DS	OF	
00002158	00001180			1734+	DC	A(T1)	address of test
0000215C	000011D8			1735+	DC	A(T2)	address of test
00002160	00001230			1736+	DC	A(T3)	address of test
00002164	00001288			1737+	DC	A(T4)	address of test
00002168	000012E0			1738+	DC	A(T5)	address of test
0000216C	00001338			1739+	DC	A(T6)	address of test
00002170	00001390			1740+	DC	A(T7)	address of test
00002174	000013E8			1741+	DC	A(T8)	address of test
00002178	00001440			1742+	DC	A(T9)	address of test
0000217C	00001498			1743+	DC	A(T10)	address of test
00002180	000014F0			1744+	DC	A(T11)	address of test



LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1787	*****
				1788	*            Register equates
				1789	*****
		00000000	00000001	1791 R0	EQU 0
		00000001	00000001	1792 R1	EQU 1
		00000002	00000001	1793 R2	EQU 2
		00000003	00000001	1794 R3	EQU 3
		00000004	00000001	1795 R4	EQU 4
		00000005	00000001	1796 R5	EQU 5
		00000006	00000001	1797 R6	EQU 6
		00000007	00000001	1798 R7	EQU 7
		00000008	00000001	1799 R8	EQU 8
		00000009	00000001	1800 R9	EQU 9
		0000000A	00000001	1801 R10	EQU 10
		0000000B	00000001	1802 R11	EQU 11
		0000000C	00000001	1803 R12	EQU 12
		0000000D	00000001	1804 R13	EQU 13
		0000000E	00000001	1805 R14	EQU 14
		0000000F	00000001	1806 R15	EQU 15
				1808	*****
				1809	*            Register equates
				1810	*****
		00000000	00000001	1812 V0	EQU 0
		00000001	00000001	1813 V1	EQU 1
		00000002	00000001	1814 V2	EQU 2
		00000003	00000001	1815 V3	EQU 3
		00000004	00000001	1816 V4	EQU 4
		00000005	00000001	1817 V5	EQU 5
		00000006	00000001	1818 V6	EQU 6
		00000007	00000001	1819 V7	EQU 7
		00000008	00000001	1820 V8	EQU 8
		00000009	00000001	1821 V9	EQU 9
		0000000A	00000001	1822 V10	EQU 10
		0000000B	00000001	1823 V11	EQU 11
		0000000C	00000001	1824 V12	EQU 12
		0000000D	00000001	1825 V13	EQU 13
		0000000E	00000001	1826 V14	EQU 14
		0000000F	00000001	1827 V15	EQU 15
		00000010	00000001	1828 V16	EQU 16
		00000011	00000001	1829 V17	EQU 17
		00000012	00000001	1830 V18	EQU 18
		00000013	00000001	1831 V19	EQU 19
		00000014	00000001	1832 V20	EQU 20
		00000015	00000001	1833 V21	EQU 21



ASMA Ver. 0.7.0 zvector-e6-11-convertbinary (Zvector E6 VRR-i)						02 Jun 2024 16:00:08 Page 41												
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES													
BEGIN	I	00000200	2	91	57	88	89											
CC	U	00000008	1	411	166													
CCFOUND	X	000010DC	1	383	153	173												
CCMASK	U	00000009	1	412	124													
CCMSG	U	00000268	1	142	136													
CCPRTEXP	C	00001086	1	363	170													
CCPRTGOT	C	00001096	1	366	177													
CCPRTLNE	C	00001043	16	358	368	180												
CCPRTLNG	U	00000055	1	368	179													
CCPRTNAME	C	00001070	8	361	163													
CCPRTNUM	C	00001053	3	359	161													
CCPSW	F	000010D4	4	382	150	543	569	595	621	647	673	699	725	751	778	804	830	
					856	882	908	934	960	986	1016	1042	1068	1094	1120	1146	1172	
					1198	1224	1250	1276	1302	1328	1354	1381	1407	1433	1459	1485	1511	
					1537	1563	1589	1615	1641	1667	1693	1719						
CTLRO	F	0000047C	4	305	101	102	103	104										
DECNUM	C	000010C4	16	378	158	160	167	169	174	176	192	194	201	203				
E6TADR	A	00000484	4	308	110													
E6TEST	4	00000000	28	406	119													
E6TESTS	F	00002158	4	1731	308													
EDIT	X	00001098	18	373	159	168	175	193	202									
ENDTEST	U	00000352	1	223	115													
EOJ	I	00000460	4	295	226													
EOJPSW	D	00000450	8	293	295													
FAILCONT	U	00000342	1	213	183													
FAILED	F	00001000	4	335	215	224												
FAILMSG	U	000002F8	1	190	131													
FAILPSW	D	00000468	8	297	299													
FAILTEST	I	00000478	4	299	227													
IMAGE	1	00000000	8736	0														
K	U	00000400	1	318	319	320	321											
K64	U	00010000	1	320														
MB	U	00000007	1	410	144	200												
MB	U	00100000	1	321														
MSG	I	00000398	4	259	242													
MSGCMD	C	000003E2	9	285	272	273												
MSGMSG	C	000003EB	95	286	266	283	264											
MSGMVC	I	000003DC	6	283	270													
MSGOK	I	000003AE	2	268	265													
MSGRET	I	000003C8	4	279	276													
MSGSAVE	F	000003D0	4	282	262	279												
NEXTE6	U	0000022A	1	112	134	218												
OPNAME	C	0000000A	8	414	163	197												
PAGE	U	00001000	1	319														
PRT3	C	000010AE	18	376	159	160	161	168	169	170	175	176	177	193	194	195	202	
					203	204												
PRTLNE	C	00001004	16	343	350	207												
PRTLNG	U	0000003F	1	350	206													
PRTM3	C	00001040	2	348	204													
PRTNAME	C	0000102F	8	346	197													
PRTNUM	C	00001014	3	344	195													
RO	U	00000000	1	1791	51	101	104	117	179	206	214	215	241	243	259	262	264	
					266	268	279	542	568	594	620	646	672	698	724	750	777	
					803	829	855	881	907	933	959	985	1015	1041	1067	1093	1119	
					1145	1171	1197	1223	1249	1275	1301	1327	1353	1380	1406	1432	1458	
					1484	1510	1536	1562	1588	1614	1640	1666	1692	1718				





SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE13	F	000015E0	4	858	848    852
RE14	F	00001638	4	884	874    878
RE15	F	00001690	4	910	900    904
RE16	F	000016E8	4	936	926    930
RE17	F	00001740	4	962	952    956
RE18	F	00001798	4	988	978    982
RE19	F	000017F0	4	1018	1008    1012
RE2	F	00001218	4	571	561    565
RE20	F	00001848	4	1044	1034    1038
RE21	F	000018A0	4	1070	1060    1064
RE22	F	000018F8	4	1096	1086    1090
RE23	F	00001950	4	1122	1112    1116
RE24	F	000019A8	4	1148	1138    1142
RE25	F	00001A00	4	1174	1164    1168
RE26	F	00001A58	4	1200	1190    1194
RE27	F	00001AB0	4	1226	1216    1220
RE28	F	00001B08	4	1252	1242    1246
RE29	F	00001B60	4	1278	1268    1272
RE3	F	00001270	4	597	587    591
RE30	F	00001BB8	4	1304	1294    1298
RE31	F	00001C10	4	1330	1320    1324
RE32	F	00001C68	4	1356	1346    1350
RE33	F	00001CC0	4	1383	1373    1377
RE34	F	00001D18	4	1409	1399    1403
RE35	F	00001D70	4	1435	1425    1429
RE36	F	00001DC8	4	1461	1451    1455
RE37	F	00001E20	4	1487	1477    1481
RE38	F	00001E78	4	1513	1503    1507
RE39	F	00001ED0	4	1539	1529    1533
RE4	F	000012C8	4	623	613    617
RE40	F	00001F28	4	1565	1555    1559
RE41	F	00001F80	4	1591	1581    1585
RE42	F	00001FD8	4	1617	1607    1611
RE43	F	00002030	4	1643	1633    1637
RE44	F	00002088	4	1669	1659    1663
RE45	F	000020E0	4	1695	1685    1689
RE46	F	00002138	4	1721	1711    1715
RE5	F	00001320	4	649	639    643
RE6	F	00001378	4	675	665    669
RE7	F	000013D0	4	701	691    695
RE8	F	00001428	4	727	717    721
RE9	F	00001480	4	753	743    747
REA1	A	00001198	4	535	
REA10	A	000014B0	4	770	
REA11	A	00001508	4	796	
REA12	A	00001560	4	822	
REA13	A	000015B8	4	848	
REA14	A	00001610	4	874	
REA15	A	00001668	4	900	
REA16	A	000016C0	4	926	
REA17	A	00001718	4	952	
REA18	A	00001770	4	978	
REA19	A	000017C8	4	1008	
REA2	A	000011F0	4	561	
REA20	A	00001820	4	1034	
REA21	A	00001878	4	1060	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES		
REA22	A	000018D0	4	1086			
REA23	A	00001928	4	1112			
REA24	A	00001980	4	1138			
REA25	A	000019D8	4	1164			
REA26	A	00001A30	4	1190			
REA27	A	00001A88	4	1216			
REA28	A	00001AE0	4	1242			
REA29	A	00001B38	4	1268			
REA3	A	00001248	4	587			
REA30	A	00001B90	4	1294			
REA31	A	00001BE8	4	1320			
REA32	A	00001C40	4	1346			
REA33	A	00001C98	4	1373			
REA34	A	00001CF0	4	1399			
REA35	A	00001D48	4	1425			
REA36	A	00001DA0	4	1451			
REA37	A	00001DF8	4	1477			
REA38	A	00001E50	4	1503			
REA39	A	00001EA8	4	1529			
REA4	A	000012A0	4	613			
REA40	A	00001F00	4	1555			
REA41	A	00001F58	4	1581			
REA42	A	00001FB0	4	1607			
REA43	A	00002008	4	1633			
REA44	A	00002060	4	1659			
REA45	A	000020B8	4	1685			
REA46	A	00002110	4	1711			
REA5	A	000012F8	4	639			
REA6	A	00001350	4	665			
REA7	A	000013A8	4	691			
REA8	A	00001400	4	717			
REA9	A	00001458	4	743			
READDR	A	00000018	4	417	129		
REG2LOW	U	000000DD	1	325			
REG2PATT	U	AABBCCDD	1	324			
RELEN	A	00000014	4	416			
RPTDWSAV	D	00000388	8	252	241	243	
RPTERROR	I	00000360	4	236	181	208	
RPTSAVE	F	00000380	4	249	236	246	
RPTSVR5	F	00000384	4	250	237	245	
SVOLDPSW	U	00000140	0	53			
T1	A	00001180	4	527	1734		
T10	A	00001498	4	762	1743		
T11	A	000014F0	4	788	1744		
T12	A	00001548	4	814	1745		
T13	A	000015A0	4	840	1746		
T14	A	000015F8	4	866	1747		
T15	A	00001650	4	892	1748		
T16	A	000016A8	4	918	1749		
T17	A	00001700	4	944	1750		
T18	A	00001758	4	970	1751		
T19	A	000017B0	4	1000	1752		
T2	A	000011D8	4	553	1735		
T20	A	00001808	4	1026	1753		
T21	A	00001860	4	1052	1754		
T22	A	000018B8	4	1078	1755		





SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V1FUDGE	X	00001140	16	396	
V1INPUT	C	00001150	16	397	
V10OUTPUT	X	000010F8	16	391	
V2	U	00000002	1	1814	
V20	U	00000014	1	1832	
V21	U	00000015	1	1833	
V22	U	00000016	1	1834	
V23	U	00000017	1	1835	
V24	U	00000018	1	1836	
V25	U	00000019	1	1837	
V26	U	0000001A	1	1838	
V27	U	0000001B	1	1839	
V28	U	0000001C	1	1840	
V29	U	0000001D	1	1841	
V3	U	00000003	1	1815	
V30	U	0000001E	1	1842	
V31	U	0000001F	1	1843	
V4	U	00000004	1	1816	
V5	U	00000005	1	1817	
V6	U	00000006	1	1818	
V7	U	00000007	1	1819	
V8	U	00000008	1	1820	
V9	U	00000009	1	1821	
X1	F	0000119C	4	537	527
X10	F	000014B4	4	772	762
X11	F	0000150C	4	798	788
X12	F	00001564	4	824	814
X13	F	000015BC	4	850	840
X14	F	00001614	4	876	866
X15	F	0000166C	4	902	892
X16	F	000016C4	4	928	918
X17	F	0000171C	4	954	944
X18	F	00001774	4	980	970
X19	F	000017CC	4	1010	1000
X2	F	000011F4	4	563	553
X20	F	00001824	4	1036	1026
X21	F	0000187C	4	1062	1052
X22	F	000018D4	4	1088	1078
X23	F	0000192C	4	1114	1104
X24	F	00001984	4	1140	1130
X25	F	000019DC	4	1166	1156
X26	F	00001A34	4	1192	1182
X27	F	00001A8C	4	1218	1208
X28	F	00001AE4	4	1244	1234
X29	F	00001B3C	4	1270	1260
X3	F	0000124C	4	589	579
X30	F	00001B94	4	1296	1286
X31	F	00001BEC	4	1322	1312
X32	F	00001C44	4	1348	1338
X33	F	00001C9C	4	1375	1365
X34	F	00001CF4	4	1401	1391
X35	F	00001D4C	4	1427	1417
X36	F	00001DA4	4	1453	1443
X37	F	00001DFC	4	1479	1469
X38	F	00001E54	4	1505	1495
X39	F	00001EAC	4	1531	1521





DESC	SYMBOL	SIZE	POS	ADDR
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**Entry: 0**

Image	IMAGE	8736	0000- 221F	0000- 221F
Regi on		8736	0000- 221F	0000- 221F
CSECT	ZVE6TST	8736	0000- 221F	0000- 221F



STMT	FILE NAME
------	-----------

```
1 /devstor/dev/tests/zvector-e6-11-convertbinary.asm
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**\*\* NO ERRORS FOUND \*\***